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COMMISSION OF THE EUROPEAN COMMUNITIES

STATISTICAL PARAMETRIC AND
NON-PARAMETRIC METHODS
OF DETERMINING THE RELIABILITY
OF MECHANICAL COMPONENTS

by

D. BASILE and G. VOLTA

1970



Joint Nuclear Research Center
Ispra Establishment - Italy
Engineering Department
Technology

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Parametrical methods were considered (applying the maximum likelihood principle) and non-parametrical methods (order statistics); particular emphasis was also given to the use of probability papers.

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ABSTRACT

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MECHANICAL STRUCTURES
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STATISTICAL PARAMETRIC AND NON-PARAMETRIC METHODS OF DETERMINING
THE RELIABILITY OF MECHANICAL COMPONENTS *)

1. INTRODUCTION

1.1 Subject Matter

The theory of reliability can be divided into two main sections. The first deals with the ways of handling the available experimental material so as to discover a posteriori the statistical law of behaviour of a component. (The notion of a "component" or "system" is not to be associated with any image of a physical complex. The component is the elementary unit under consideration, for which the statistical law of behaviour is to be defined. The system is the result of the functional connexion of a number of components.)

The second section starts from the assumption of knowledge of the statistical properties of the components to deduce, by means of appropriate probabilistic models that simulate the functional relations between components, the properties of a system.

This report is a contribution to the first section. To process the experimental material, which consists of data (lifetime, breaking stresses, etc.) corresponding to events considered as random, one uses statistical methods already developed to a large extent for an immense variety of applications. The specific application of these mathematical methods to reliability problems depends on the type of component in question, the context and the purpose of the application.

The method that can and must be employed to assess the reliability of mass-produced electronic components in a design study for a data bank, for instance, is of little use to someone who wants to evaluate the reliability of mechanical components of a plant in operation so that the management can be duly adjusted at once.

*) Manuscript received on 2 March 1970

In this report we adopted the position of someone concerned with the reliability of mechanical and electromechanical components, i.e., components for which:

- the dimensions of the available sample are always fairly small;
- the deterioration of the properties (through wear, corrosion, fatigue, etc.) with time is significant with respect to the lifetimes regarded as useful;
- the reliability analysis effected during operation, taking into account the damage that has occurred on only a fraction of a series of functioning components, can be of more immediate interest than the reliability analysis that can be obtained when the sampling procedure is completed in full.

Adopting this point of view, to which is not yet given enough consideration in the literature on reliability, we have set out the typical and suitable methods of analysis, developing for each the appropriate digital programmes.

1.2 Plan of the Report

Section 2 briefly describes the main outlines of what are called parametric methods for the statistical analysis of samples, i.e., the methods most commonly used in the case of large numbers of samples. We have dwelt more particularly on the application of these methods to cases of exponential and Weibull distributions of failure.

The range of reference works available for this matter is enormous as far as the general principles are concerned, but is far more limited when it comes to specific application to Weibull distributions. We referred chiefly to the excellent book by Lloyd and Lipow (Ref. 1).

Section 3 shows a non-parametric method which can be regarded as a direct application of a general property of the statistical variables associated with ordered events (order statistics).

This method has been insistently advocated and illustrated by L.G. Johnson (Refs. 2 and 3) of General Motors, precisely in the context of its application to mechanical components.

The method is extremely simple when suitable tabulated values are available; for small samples it is better than the parametric methods and, unlike them, enables one to take into consideration incomplete samples, such as occur in the case of a set of in-service components only a fraction of which is damaged. We describe the method and have also developed a digital programme by which the tabulated values can be obtained for samples composed of 1-50 elements and for various degrees of confidence.

Section 4 contains a critical analysis of the method of "probability papers", a method which combines the advantages of the non-parametric method with the potentialities inherent to the parametric methods. For this method we referred principally to the works by Gumbel (Ref. 4) and Weibull (Ref. 5).

Lastly, in Section 5, the various methods mentioned are applied to some real cases and the results are compared with reference to the extreme values.

1.3 Some General Concepts

1.3.1 Definition of reliability

Out of the various definitions of reliability we quote the one adopted by the IEC: "The characteristic of an item expressed by the probability that it will perform a required function under stated conditions for a stated period of time". The probability indicated, a function of time, is the complement to 1 of the probability of non-function or probability of failure.

Considerations on reliability are based on the considerations on the failure distribution, since the failure is the physically observed event.

1.3.2 Failure distribution function and failure rate function

The functions of failure distribution versus time are also indicated as life characteristics of the given component. We shall take $F(t)$ to be the failure distribution, i.e., the probability that the component will fail before time t , and $f(t)$ the corresponding density. It is also expedient to introduce a "failure rate" $v(t)$ defined as

$$v(t) = \frac{f(t)}{1 - F(t)}$$

This function is also known as the "force of mortality", "mills ratio", "intensity function" or "hazard rate". The failure rate function is useful because amongst other things, it allows of dividing the distribution functions into two main categories - the failure rate functions that increase with time, and those that decrease with time.

The fact of belonging to one or other of these categories has an immediate physical significance: an increasing f.r.f. corresponds to the existence of wear or fatigue phenomena, a decreasing f.r.f. to the running-in situation, for instance; but the subdivision also has an important formal significance: one need only know that a distribution belongs to one or the other category to be able to deduce limit statistical properties of the component concerned or of the system consisting of a number of components (Ref. 6).

1.3.3 Most commonly used continuous failure distributions

Exponential distribution

$$F(t) = 1 - e^{-\lambda t} \quad t \geq 0, \lambda > 0$$

$$f(t) = \lambda e^{-\lambda t}$$

$$v(t) = \lambda$$

$$\text{Mean} = 1/\lambda = \tau$$

Weibull distribution

$$F(t) = 1 - e^{-\lambda(t-\theta)^\alpha} \quad t \geq 0, \theta \geq 0, \lambda > 0, \alpha > 0$$

$$f(t) = \lambda \alpha (t-\theta)^{\alpha-1} e^{-\lambda(t-\theta)^\alpha}$$

$$v(t) = \lambda \alpha (t-\theta)^{\alpha-1}$$

$$\text{Mean} = \lambda^{1/\alpha} \Gamma(1+1/\alpha)$$

Normal distribution

$$F(t) = \int_{-\infty}^t \frac{1}{\sqrt{2\pi} \sigma} e^{-\frac{1}{2} \left(\frac{t-\mu}{\sigma}\right)^2} dt$$

$$f(t) = \frac{1}{\sqrt{2\pi} \sigma} e^{-\frac{1}{2} \left(\frac{t-\mu}{\sigma}\right)^2}$$

$$v(t) = \frac{e^{-\frac{1}{2} \left(\frac{t-\mu}{\sigma}\right)^2}}{\int_t^{\infty} e^{-\frac{1}{2} \left(\frac{t-\mu}{\sigma}\right)^2} dt}$$

$$\text{Mean} = \mu$$

Log-normal distribution

If $y = \ln t$ is a normal variate with mean μ and variance σ^2 , the distribution of t is known as log-normal:

$$F(t) = \frac{1}{\sigma \sqrt{2\pi}} \int_{-\infty}^{\ln t} e^{-\frac{1}{2} \left(\frac{y-\mu}{\sigma}\right)^2} dy$$

$$= \frac{1}{\sigma \sqrt{2\pi}} \int_0^t e^{-\frac{1}{2} \left(\frac{\ln t - \mu}{\sigma}\right)^2} \frac{dt}{t}$$

$$f(t) = \frac{1}{t} \frac{1}{\sigma \sqrt{2\pi}} e^{-\frac{1}{2} \left(\frac{\ln t - \mu}{\sigma}\right)^2}$$

$$\text{Mean} = e^{\mu + \sigma^2/2}$$

The exponential distribution is characterized by a constant rate of failure function (λ). The reciprocal of λ is the mean time between two failures (MTBF).

This law interprets failure phenomena corresponding to purely random events and it also interprets phenomena of failure of complex systems, when the number of components tends to become very large, independently of the law of failure of the individual components. Furthermore it takes advantage of the fact that a system consisting of components characterized by an exponential law will likewise have an exponential failure law.

The normal and log-normal distributions are used mainly to interpret failure phenomena due to wear. They are characterized by failure rate functions that increase with time.

The Weibull distribution, with three parameters, is more flexible than the foregoing ones. Its limit case, for $\alpha = 1$, is the exponential distribution, and it too can be used to interpret failure due to wear. Moreover it is suitable for a linear representation on log-log paper, so that it does not require special probability papers. Lastly it is an asymptotic distribution of the extreme values of a wide class of distributions (Ref. 4), for which reason it appears in particular to be inherently suited to represent the phenomena of material failure, interpreted as the failure of the weakest link in a chain.

For these reasons this distribution, proposed originally by Weibull to interpret data on tensile and fatigue failure of materials, has been increasingly used in the field of electro-mechanical components which we shall be considering in particular.

1.3.4 The reliability function

The reliability function R is defined as the difference between the failure distribution values corresponding to the extremes of the event (period of time intended and operating conditions encountered).

$$R = F(t_2) - F(t_1)$$

In general one assumes for the time interval (t_2, t_1) , (∞, T) , so that:

$$R(T) = 1 - F(T)$$

The time T is often indicated as "mission time".

On the basis of this definition $R(t)$ is to be deduced straightaway in the cases $F(t)$ indicated.

2. PARAMETRIC METHODS

2.1 General Scheme

The term "parametric" applied to these methods is due to the fact that, starting from the sample, they evaluate the parameters of the distribution of failure and hence of reliability, a distribution hypothesized a priori. Roughly speaking, their stages of use are as follows:

i) availability of a complete set^(*) of values (sample) referring

(*) An incomplete set is one of defined dimensions but only partially defined values. Take, for instance, a fixed number of components being tested simultaneously. The set of lifetimes will be complete when the last surviving component fails; it will be incomplete for all the preceding times.

to the component's characteristic used for the reliability estimate (lifetime, breaking stress, etc.). These values obviously have to be obtained from tests or operating experience on components belonging to the same statistical population.

- ii) Assumption of one or more forms of statistical distribution to which the sample is assumed to belong.
- iii) Estimate of the distribution parameters, based on the sample values. The most practical and suitable procedure for this purpose is the one based on the principle of maximum likelihood.
- iv) Test for goodness of fit on the various assumed distributions to see which one fits the interpretation of the sample best for a given significance level.
- v) Determination of the variances of the estimated parameters and, if appropriate, of their confidence intervals.
- vi) Calculation of the reliability value, by means of the distribution adopted and the estimated parameters. This reliability value will likewise be an estimated value. Hence a confidence interval will have to be established for it.

2.2 Estimate of Parameters

2.2.1 The maximum-likelihood method

This very general method is mentioned in all textbooks on statistics. Considering, for simplicity's sake, a distribution with a single parameter α , $f(t, \alpha)$, of which the mathematical form is assumed to be known, we form from the sample (t_1, t_2, \dots, t_n) the function

$$L(t_1, t_2, \dots, t_n; \alpha) = \prod_{i=1}^n f(t_i, \alpha) \quad (1)$$

known as the function of likelihood of the sample. It corresponds to the compound probability of n random independent variables, each with the same probability distribution, i.e., it corresponds to the probability of obtaining the sample under study out of all the possible samples of the same size. The method consists in determining which value of the parameter α renders it most probable that the sample under study will turn up. Thus, if we call that value α^* it must satisfy the equation

$$\left(\frac{\partial L}{\partial \alpha}\right)_{\alpha=\alpha^*} = 0 \quad (2)$$

(or $\frac{\partial \mathcal{L}}{\partial \alpha} = 0$ with $\mathcal{L} = \log L$)

known as the likelihood equation.

Under very general conditions, the maximum-likelihood estimate has a normal distribution when the sample dimensions tend to ∞ . This asymptotic property of the maximum-likelihood estimates is most useful, because it means that the properties characteristic of a normal distribution can be attributed to those estimates. At the same time, inasmuch as it is an asymptotic property, it is the chief limitation of the method, since small samples cannot be taken into consideration (according to Ref. 1, page 172, the correct use of the normal approximation calls for sample sizes of not less than 50).

2.2.1 Determination of the variances of the estimated parameters

A distribution dependent on two parameters α, λ is considered. Let $\hat{\alpha}$ and $\hat{\lambda}$ be the values of these parameters estimated by the maximum-likelihood method from the sample values. It has been shown (Ref. 7) that by using the asymptotic property of the estimated parameters, approximated values of the $\hat{\alpha}$ and $\hat{\lambda}$ variances are obtained by constructing the matrix

$$A = \begin{vmatrix} \frac{\partial^2 \mathcal{L}}{\partial \alpha^2} & \frac{\partial^2 \mathcal{L}}{\partial \alpha \partial \lambda} \\ \frac{\partial^2 \mathcal{L}}{\partial \alpha \partial \lambda} & \frac{\partial^2 \mathcal{L}}{\partial \lambda^2} \end{vmatrix} \quad (3)$$

Between A and matrix

$$B = \begin{vmatrix} \text{Var } \hat{\alpha} & \text{Cov}(\hat{\alpha}, \hat{\lambda}) \\ \text{Cov}(\hat{\alpha}, \hat{\lambda}) & \text{Var } \hat{\lambda} \end{vmatrix} \quad (4)$$

there is the simple relation:

$$B = -A^{-1} \quad (5)$$

It will be noted that A is a function of the real parameters α, λ ; approximated values are obtained by substituting for the real, unknown values the estimated values $\hat{\alpha}, \hat{\lambda}$. In the case where the distribution depends on a single parameter α , we obtain from the foregoing formulae:

$$\text{Var } \hat{\alpha} = - \left(\frac{\partial^2 \mathcal{L}}{\partial \alpha^2} \right)^{-1} \quad (6)$$

2.3 Goodness of Fit

The choice of the form of distribution to which the data are assumed to belong is, a priori, arbitrary. Hence, the distributions adopted, whose parameters have been estimated on the basis of the sample, must be tested to decide which fits best with the sample. Let us briefly describe two widely used tests, namely the chi-squared test and the Kolmogoroff test. The first applies to the density of distribution, the second to the distribution. The efficiency of both methods is limited by the size of the sample. The first method is not applicable

to small samples because it calls for division of the sample into classes and calculation of the frequency for each class. The second method does not have this drawback. But being based on asymptotic properties, neither is very significant when it comes to small samples.

2.3.1 The chi-squared test (Ref. 8)

The data for the sample of size n are classified in k intervals

$$t_i \pm \frac{\Delta t_i}{2} \quad i = 1, \dots, k$$

and the values v_i are considered, corresponding to the number of sample data comprised in the i -th generic interval.

If $f(t)$ is the density function of the assumed distribution

$$P_i = \int_{t_i - \Delta t_i/2}^{t_i + \Delta t_i/2} f(t) dt \quad (7)$$

will represent the probability that the statistical variable in question belongs to the i -th interval.

If the assumption concerning the distribution is valid, then

$$\lim_{n \rightarrow \infty} P(|v_i - np_i| < \epsilon) = 1 \quad (8)$$

Hence a measurement of the data's goodness of fit with the hypothesis is related to the complex of differences $(v_i - np_i)$.

With a choice owed to Pearson, we can establish the following magnitude as the measurement of this goodness of fit:

$$\Delta^2 = \sum_{i=1}^k \frac{(v_i - np_i)^2}{np_i} \quad (9)$$

and it can be shown that Δ^2 is a random variable distributed, with $n \rightarrow \infty$, according to a χ^2 law with $k-1$ degrees of freedom, in the event that the parameters of the assumed distribution are known.

If, on the other hand, the parameters are estimated from the sample, the number of degrees of liberty will be lower than $k-1$ by as many units as there are estimated parameters.

For practical application of the test, having calculated Δ^2 and set a level of significance γ , we find from the tables a value χ_γ^2 such that:

$$P(\chi^2 \geq \chi_\gamma^2) = \gamma \quad (10)$$

The assumed distribution satisfies the test if

$$\Delta^2 < \chi_\gamma^2$$

For a valid application of the test the sample dimensions must be such that

$$np_i > 10 \quad i = 1, \dots, k$$

2.3.2 Kolmogoroff test (Ref. 9)

This is a test which examines the cumulative distribution. Let $F(t)$ be this distribution assumed to be continuous and let $S_n(t)$ be the empirical distribution of the sample of dimensions n , arranged in ascending order of values.

Furthermore let:

$$D_n = \max_{-\infty < x < \infty} |F(t) - S_n(t)| \quad (11)$$

$$Q(\lambda) = \sum_{-\infty}^{\infty} \frac{1}{k} (-1)^k e^{-2k^2 \lambda^2} \quad \lambda > 0 \quad (12)$$

The test is based on Kolmogoroff's theorem which states:

$$\lim_{n \rightarrow \infty} P(D_n < \frac{\lambda}{\sqrt{n}}) = Q(\lambda) \quad (13)$$

For application purposes, once D_n has been calculated and a level of significance α has been chosen, we find in the tables value λ_α for which

$$Q(\lambda_\alpha) = 1 - \alpha \quad (14)$$

The distribution in question will satisfy the test if

$$D_n < \lambda_\alpha / \sqrt{n}$$

In Appendix 1 will be found the description of the KTEST code, programmed in IBM 360/65 to effect the Kolmogoroff test on various distributions. The normal, log-normal, Weibull and exponential distributions are considered.

2.4 Reliability Estimate

When the failure distribution parameters have been estimated, we can estimate the reliability value corresponding to a time T.

$$\hat{R}(T) = R(\hat{\alpha}, \hat{\lambda}, T)$$

Now comes the problem of evaluating the confidence we can have in this estimate.

The general method, which is valid only for numerous samples and does not require knowledge of the distribution of the parameter estimates, i.e., of $\hat{\alpha}$, $\hat{\lambda}$, etc., makes use of R's

property of being asymptotically normal (Ref. 1, page 192). Hence it is necessary to know $E(\hat{R})$ and $\text{Var } \hat{R}$, i.e., the mean value and variance of the estimate.

It has been shown (Ref. 10, page 354) that

$$E[R(\hat{\alpha}, \hat{\lambda})] = R(\alpha, \lambda) + O(1/n) \quad (15)$$

$$\text{Var}[R(\hat{\alpha}, \hat{\lambda})] = \left(\frac{\partial R}{\partial \alpha}\right)_{\alpha}^2 \text{Var } \hat{\alpha} + \left(\frac{\partial R}{\partial \lambda}\right)_{\lambda}^2 \text{Var } \hat{\lambda} + \quad (16)$$

$$+ 2\left(\frac{\partial R}{\partial \alpha}\right)_{\alpha} \left(\frac{\partial R}{\partial \lambda}\right)_{\lambda} \text{Cov}(\hat{\alpha}, \hat{\lambda}) + O(1/n^{1.5})$$

Both $O(1/n^{1.5})$ and $O(1/n)$ are terms which tend towards zero as the sample dimensions increase. An estimate of $E(\hat{R})$ and $\text{Var}(\hat{R})$ can be obtained by substituting $\hat{\alpha}, \hat{\lambda}$, for α, λ in (15) and (16).

This general procedure is not necessary in cases where the reliability is a function of a single parameter (see exponential distribution). In such a case a reliability confidence interval can be found directly from the parameter confidence interval. For this purpose one must know the parameter distribution or else apply the property of normal asymptotic behaviour of the estimate using the variance calculated in Section 2.2.1.

2.5 Applications

2.5.1 Exponential distribution

The failure distribution density is given by:

$$f(t, \lambda) = \lambda e^{-\lambda t} \quad t \geq 0, \lambda > 0$$

Starting from the sample (t_1, \dots, t_n) the maximum-likelihood function will be:

$$L = \lambda^n e^{-\lambda \sum_i t_i} \quad (17)$$

and from the maximum-likelihood equation

$$\frac{\partial \log L}{\partial \lambda} = 0$$

we obtain

$$\frac{1}{\hat{\lambda}} = \frac{\sum_i t_i}{n} \quad (18)$$

i.e., the mean of the sample is the inverse of the estimate of parameter λ . An estimated value of the reliability at time T will be given by:

$$\hat{R} = R(T, \hat{\lambda}) = e^{-\hat{\lambda}T} \quad (19)$$

The calculation of the confidence interval of this estimate can be done by two different routes as already mentioned in Section 2.4. One procedure, which we might call general, entails calculation of the variance of the distribution parameter, followed by calculation of the \hat{R} variance and, using the normal approximation, the \hat{R} confidence interval. From (6) we obtain

$$\text{Var } \hat{\lambda} = - \left(\frac{\partial^2 \log L}{\partial \lambda^2} \right)^{-1} = \frac{\lambda^2}{n}$$

and from (15) and (16)

$$E(\hat{R}) = e^{-\lambda T}$$

$$\text{Var } \hat{R} = \left(\frac{\partial \hat{R}}{\partial \lambda} \right)^2 \text{Var } \hat{\lambda} = \frac{\lambda^2 T^2}{n} e^{-2T\lambda}$$

$$\sigma_{\hat{R}} = \frac{T\lambda}{\sqrt{n}} e^{-\lambda T} = \frac{R \log 1/R}{\sqrt{n}} \approx \frac{\hat{R} \log 1/\hat{R}}{\sqrt{n}}$$

The variable

$$\eta = \frac{\hat{R} - E(\hat{R})}{\sigma_{\hat{R}}} \quad (20)$$

is asymptotically a standardized normal variate. Having established a confidence level γ , we find the confidence interval for the reliability:

$$\hat{R} \pm \frac{\sigma_{\hat{R}}}{R} \cdot n^{(1+\gamma)/2}$$

A second procedure, valid only in the case of exponential distribution, allows one to avoid the repeated use of the asymptotic approximations employed in the previous procedure.

This second route is based on two characteristics of the exponential distribution:

- the distribution of the estimated parameter $\hat{\lambda}$ is known;
- the reliability is a monotonic function of the parameter.

It has been shown (Ref. 11, page 190) that the estimated parameter $\hat{\tau} = \frac{1}{\lambda}$ has a gamma distribution:

$$P(\hat{\tau} \leq x) = \frac{1}{\Gamma(n)} \int_0^x \left(\frac{n}{\tau}\right)^n t^{n-1} e^{-n \frac{t}{\tau}} dt \quad (21)$$

by putting $\chi^2 = 2n \frac{\hat{\tau}}{\tau}$ this distribution can be reduced to a chi-squared distribution with $2n$ degrees of freedom. Thus (21) is equivalent to:

$$P(\chi^2 \leq y) = \frac{1}{2^n \Gamma(n)} \int_0^y t^{n-1} e^{-t/2} dt \quad (22)$$

By using (22) we can obtain an exact evaluation of the confidence limit on $\hat{R} = R(\hat{\tau})$ at a given confidence level γ . For having fixed a value for γ , we obtain from (22):

$$P\left(\frac{2n\hat{\tau}}{2} < \tau\right) = \gamma \quad (23)$$

Thus $\hat{\tau}_i = \frac{2n\hat{\tau}}{2} \chi_{1-\gamma}^2$ represents a lower limit of τ with confidence level γ .

As the reliability $R = e^{-T/\tau}$ is an increasing function of τ , it follows that a lower limit for the reliability at time T , with confidence level γ , will be given by:

$$R(\hat{\tau}_i) = e^{-\frac{T \chi_{1-\gamma}^2}{2n \hat{\tau}_i}} \quad (24)$$

It is important to note that we have been able to transfer to the reliability the confidence limit calculated for $\hat{\tau}$ only inasmuch as the distribution has only one parameter. In general this is not possible where there is more than one parameter.

2.5.2 Weibull distribution

The most general form of this distribution has three parameters:

$$F(t) = 1 - e^{-\lambda(t-\theta)^\alpha}$$

for the sake of simplicity, we shall assume $\theta = 0$; the probability density function therefore is:

$$f(t) = \alpha \lambda t^{\alpha-1} e^{-\lambda t^\alpha} \quad t \geq 0, \alpha > 0, \lambda > 0$$

The log of the likelihood function, for a sample (t_1, \dots, t_n) is given by:

$$\mathcal{L} = n \log \alpha + n \log \lambda + (\alpha-1) \sum_{i=1}^n \log t_i - \lambda \sum_{i=1}^n t_i^\alpha \quad (25)$$

By imposing the maximum likelihood conditions on \mathcal{L} :

$$\frac{\partial \mathcal{L}}{\partial \alpha} = 0 \quad \frac{\partial \mathcal{L}}{\partial \lambda} = 0$$

we get two equations for the determination of the estimated values $\hat{\alpha}, \hat{\lambda}$, of the two parameters:

$$\hat{\lambda} = \frac{n}{\sum t_i^{\hat{\alpha}}} \quad (26)$$

$$\hat{\alpha} = \frac{n}{\hat{\lambda} \sum t_i^{\hat{\alpha}} \log t_i - \sum \log t_i} \quad (27)$$

The calculation of $\hat{\alpha}$ and $\hat{\lambda}$ from these equations is done with an iteration process programmed on IBM 360/65. To obtain a reasonable initial value for $\hat{\alpha}$ the following relation is used, which expresses equality between the sample mean and the distribution mean:

$$\frac{1}{n} \sum t_i = \lambda^{-1/\alpha} \Gamma(1 + \frac{1}{\alpha}) \quad (28)$$

To determine the variance and covariance of the two parameters it is necessary to invert the matrix

$$\begin{vmatrix} \frac{\partial^2 \mathcal{L}}{\partial \alpha^2} & \frac{\partial^2 \mathcal{L}}{\partial \alpha \partial \lambda} \\ \frac{\partial^2 \mathcal{L}}{\partial \alpha \partial \lambda} & \frac{\partial^2 \mathcal{L}}{\partial \lambda^2} \end{vmatrix} \quad (29)$$

Having calculated $\text{Var } \hat{\alpha}$, $\text{Var } \hat{\lambda}$, $\text{Cov}(\hat{\alpha}, \hat{\lambda})$ in this way, we can find the variance of the estimated reliability value. If T is the mission-time for the component for which the reliability is to be ascertained, then the estimated reliability value is

$$\hat{R} = e^{-\hat{\lambda} T^{\hat{\alpha}}}$$

Also, by reference to (15) and (16)

$$E(\hat{R}) = e^{-\lambda T^{\alpha}} \quad (30)$$

$$\text{Var } \hat{R} = T^{2\alpha} e^{-2\lambda T^\alpha} (\lambda^2 \log^2 T \text{Var } \hat{\alpha} + \text{Var } \hat{\lambda} + 2\lambda \log T \text{Cov}(\hat{\alpha}, \hat{\lambda})) \quad (31)$$

Estimated values for $E(\hat{R})$ and $\text{Var } \hat{R}$ can be obtained by replacing α and λ in the previous equations with their estimates $\hat{\alpha}$ and $\hat{\lambda}$.

Using the normal approximation we can then find a confidence interval for \hat{R} .

The foregoing calculations have been programmed on IBM 360/65. Appendix 2 gives a description of the VITA code employed.

3. NON-PARAMETRIC METHODS

3.1 General

Given a fairly small sample (with fewer than, say, 20 values) the mathematically laborious method described in the previous chapter yields results whose significance is not proportionate to the effort required.

The method we shall give here, however, enables the reliability corresponding to the measured values to be easily and directly evaluated, even with very small samples.

It also permits of evaluating a confidence interval, likewise in respect of the measured values.

Lastly, it allows the sample size to be taken into account in cases where the sample is incomplete: from this standpoint it offers a possibility not allowed by the method described in the previous chapter.

On the other hand, as it does not aim to evaluate the distribution but confines itself to evaluation of a series of discrete values, it does not provide indications for interpolation or extrapolation.

3.2 Statistical Properties of Ordered Samples

3.2.1 Distribution of the m-th value

Let $(t_1, \dots, t_m, \dots, t_n)$ be a sample of size n with values in order of increase. The distribution $\bar{\Phi}(t)$ from which the sample was taken is unknown. The problem is to estimate the cumulative probability $\bar{\Phi}(t_m)$, using for the purpose the sample's property of being ordered. If the population is sampled again, the value t'_m , arrayed in the m -th position, will in general be different from t_m and one can say that the sample order position m characterizes, by means of all the samples extractable from the population, a set of values, the t_m values, which will be distributed according to their own law of probability, whose density is:

$$\psi_n(t_m) = m \binom{n}{m} \phi^{m-1}(t_m) [1 - \phi(t_m)]^{n-m} \phi'(t_m) \quad (1)$$

This law can be determined at once by using the polynomial distribution and the sample's property of order. It is a known fact that, given three events with probabilities p_1 , p_2 and p_3 at the instant of a test, the probability that in n tests the event with probability p_1 will occur n_1 times, that of probability p_2 n_2 times, and that of probability p_3 n_3 times is:

$$\frac{n!}{n_1! n_2! n_3!} p_1^{n_1} p_2^{n_2} p_3^{n_3}$$

If we now let the event "value of t lying between t_m and $t_m + dt_m$ " correspond to p_1 , then

$$p_1 = \xi(t_m) dt_m$$

where $\xi(t) = \phi'(t)$

Similarly let the event "value of $t \leq t_m$ " correspond to p_2 , then

$$p_2 = \phi(t_m)$$

and lastly let the event "value of $t > t_m$ " correspond to p_3 , so that

$$p_3 = 1 - \phi(t_m)$$

If $n_1 = 1$, $n_2 = m - 1$, $n_3 = n - m$, the probability law obtained is actually that of the population of t_m values represented by (1). Naturally (1) and therefore the mean \bar{t}_m , the median \check{t}_m and the modal value \tilde{t}_m are unknown, in our case, because $\phi(t)$ is unknown.

3.2.2 Probability distribution for m-th value

By performing in (1) the variate transformation

$$\phi_m = \phi(t_m) \tag{2}$$

we obtain

$$\chi_n(\phi_m) = m \binom{n}{m} \phi_m^{m-1} (1-\phi_m)^{n-m} \tag{3}$$

in which

$$0 \leq \phi_m \leq 1$$

Thus $\chi_n(\phi_m)$ represents the probability density for the distribution of the cumulative probability values appropriate to the values of t_m .

The chief interest of (3) lies in the fact that the ϕ_m distribution does not depend on the unknown $\phi(t)$ distribution.

It will be recognized that $\chi_n(\phi_m)$ is a beta distribution.

In general the probability density for the beta distribution is:

$$\xi(x) = \frac{\Gamma(\alpha+\beta+2)}{\Gamma(\alpha+1)\Gamma(\beta+1)} x^\alpha(1-x)^\beta$$

for $0 \leq x \leq 1$ with entire $\alpha, \beta > -1$.

With $\alpha = m - 1$ and $\beta = n - m$ one obtains expression (3).

3.2.3 Estimate of the $\phi(t_m)$ probability - Median ranks

If $\eta(p)$ is taken to represent the cumulative distribution of ϕ_m , then

$$\eta(p) = \int_0^p \chi_n(\phi_m) d\phi_m$$

It is readily apparent that, integrating item by item successively, we shall obtain

$$\eta(p) = \sum_m^n \binom{n}{i} p^i (1-p)^{n-i} \quad (4)$$

or

$$\eta(p) = 1 - \sum_0^{m-1} \binom{n}{i} p^i (1-p)^{n-i} \quad (5)$$

Relation (5) enables us to solve the problem stated at the outset, namely, that of obtaining an estimate of the probability $\phi(t_m)$ and assigning a confidence level for that estimate.

For in (5), p is a value of ϕ_m such that the probability of a value $\phi_m \leq p$ is $\eta(p)$; hence it can be said that p is the estimate of $\phi(t_m)$ with confidence level $\eta(p)$.

In other terms this means that if we assign the cumulative probability p to the sample observation t_m , there will be $100 \eta(p)$ samples, out of 100 extractable from the population, in which the value $\phi(t_m)$ will be lower than p . It is perhaps needless to remark that the use of (5) to estimate $\phi(t_m)$ does not entail

knowledge of the value t_m ; it is merely assumed that t_m is the largest of the m values observed, i.e., that the sample is ordered in increasing values.

Hence (5) lends itself to the construction of tables for p , each one characterized by a value of $\eta(p)$. These are double-entry tables in which, for every n , the p values are given in line with $m = 1, 2, \dots, n$. It can be shown that with $\eta(p)$, m , n fixed, there is a single solution of (5) lying between 0 and 1.

Appendix 3 gives the text of the RANKS programme processed on IBM 360/65 for the solution of (5), and also, for $\eta(p) = .05, .5, .95$, the tables of the p values obtained, for sample sizes up to 20. The p values obtained with $\eta(p) = .5$ are known as "median ranks" and are particularly recommended by Johnson (Refs. 2 and 3), who was the first to use them. An interesting aspect of (5) is that confidence belts can be constructed. For this purpose the tables for $\eta(p) = .05$ and $.95$ are provided. Their use is immediate: they permit of stating that the unknown real probability $f(t_m)$ lies, with 90% probability, in the interval bounded by $m^P .95$ and $m^P .05$.

3.2.4 Mean ranks and modal value

Other interesting aspects of the distribution of the cumulative probabilities $\eta(p)$ can be found by calculating, in addition to the median already noticed, the mean value and the modal value; as regards the mean value we have:

$$\bar{\phi}_m = \int_0^1 \chi_n(\phi_m) \phi_m d\phi_m \quad (6)$$

Noting that:

$$\int_0^1 \phi_m^m (1-\phi_m)^{n-m} d\phi_m = \frac{\Gamma(m+1) \Gamma(n-m+1)}{\Gamma(n+2)}$$

we have

$$\bar{\phi}_m = m \binom{n}{m} \frac{m!(n-m)!}{(n+1)!} = \frac{m}{n+1} \quad (7)$$

The modal value is obtained from (3) as the solution of $\chi'_n = 0$:

$$\tilde{\phi}_m = \frac{m-1}{n-1} \quad (8)$$

The advantage of these estimates as against the median ranks is their very simple form which permits of immediate calculation for all values of m and any size of sample.

Furthermore the confidence level which, by means of (5), can be associated with each estimate is not constant as for the median ranks, but varies with m or with the sample size.

4. METHOD OF PROBABILITY PAPERS

4.1 General

This method has the same objectives as the method described in Section 2, i.e., it aims at deriving a distribution from the sample.

As in the parametric method, the first step in this method is to choose a form of distribution, and then to select a "paper" in which that form of distribution is linear.

Having chosen the paper and therefore the linearization of the function, we now have to represent the sample values.

Next we trace, by means of a suitable regression, the straight line which best interpolates these points, and in this way we obtain the parameters of the desired basic distribution.

4.2 Linearization

Let $\Phi(t, \alpha, \beta)$ be the cumulative probability of a statistical variable t and let α, β be the distribution parameters. If there is a linear transformation

$$y = \alpha(t - \beta) \quad (1)$$

such that the distribution

$$F(y) = \Phi(\beta + y/\alpha, \alpha, \beta) \quad (2)$$

is independent of the parameters α, β , it is possible to construct a probability paper for the distribution Φ . On this $\Phi(t, \alpha, \beta)$ will then be represented by the straight line (1). $F(y)$ is called the "standard form" of the distribution and is usually tabulated. If there are three parameters α, β, γ , there is more than one linearization possible. For instance in the case of a complete Weibull distribution

$$W(t) = 1 - e^{-[(t-\beta)\alpha]^\gamma} \quad (3)$$

it is possible, for each fixed value of γ , to effect the linearization (1) and hence to refer to a standard form relating to the fixed γ value. Generally, however, the Weibull distribution is used in the incomplete form obtained with $\beta = 0$. Obviously linearization of type (1) is then out of the question. In that case we effect a logarithmic transformation which leads to

$$\frac{1}{\gamma} \log \ln \frac{1}{1-W(t)} = \log t + \log \alpha \quad (4)$$

which on log-log paper with coordinates $t, \ln \frac{1}{1-W(t)}$ is a linearization of (3). In this case one can no longer speak of a standard form for the distribution.

4.3 The Plotting Position

As already remarked, the crucial problem in using probability papers lies in the choice of the probability value to assign to the generic value of the sample. It will be seen that the manner of choice can be exacting, taking into account the type of distribution that the data have to fit, or approximate (although fulfilling certain criteria), disregarding that distribution.

4.3.1 Distribution-dependent plotting

We have already seen in Section 3 that in an ordered sample of size n the m -th position designates, through all the possible ordered samples extractable from the population, a new distribution, that of the m -th value, whose density function is:

$$\psi_n(t_m) = m \binom{n}{m} \phi^{m-1}(t_m) [1 - \phi(t_m)]^{n-m} \phi'(t_m) \quad (5)$$

the transformation (1) will provide a value corresponding to each t_m , namely

$$y_m = \alpha(t_m - \beta) \quad (6)$$

belonging to the distribution of the m -th reduced value.

Applying the mean operator to (6), we obtain:

$$E(t_m) = \beta + \frac{1}{\alpha} E(y_m) \quad (7)$$

The plotting position proposed by Weibull (Ref. 5, p. 198) is

$$P_m = F(E(y_m)) \quad (8)$$

F being distribution (2), i.e., the standard form of the hypothesized distribution.

Consequently, with the m -th observation of the ordered sample we must associate a cumulative probability given by the

value of the standard distribution at the mean of the reduced variables relating to the m -th position; the least squares will therefore be effected on the points $t_m, E(y_m)$. The mean $E(y_m)$ must be calculated from the distribution of y_m which is determined by $F(y)$ and is thus independent of the unknown parameters. The distribution of y_m is found by operating in (5) the change of variables given by (1):

$$\theta_n(y_m) = m \binom{n}{m} F^{m-1}(y_m) [1 - F(y_m)]^{n-m} F'(y_m) \quad (9)$$

Hence

$$E(y_m) = \int_{-\infty}^{\infty} y_m \theta_n(y_m) dy_m \quad (10)$$

or else, writing

$$F(y) = u, \quad y = G(u) \quad (11)$$

$$E(y_m) = \int_0^1 \binom{n}{m} G(u) u^{m-1} (1-u)^{n-m} du \quad (12)$$

It will be seen from (12) that $E(y_m)$ depends only on m, n and on the standard form of the assumed distribution. If the plotting position (8) is used and the fitting is done with the least-squares method (minimizing the deviations Δt_1) the estimates $\hat{\alpha}, \hat{\beta}$, are not affected by systematic errors (Ref. 5, p. 198). It must be pointed out that position (8) can only be used when the distribution can be brought to a standard form by means of (1). This is not the case, for instance, with the usual Weibull distribution, with $\beta = 0$ (see (3)).

4.3.2 Distribution-independent plotting

Whilst the plotting position (8) recommended by Weibull is the strictest because it does not introduce systematic errors in the parameter estimates, it has the drawback of depending on

the preselected form of distribution and hence of requiring the use of tables of the values $E(y_m)$.

Where these tables are not available and one can make do with a certain degree of approximation in the estimate, it is possible to use other plotting positions which are independent of the distribution and have very simple forms.

For example, if the sample is in order of increasing values we can, by convention, assign the cumulative probability m/n to the ordered value t_m . If, on the other hand, the sample is in order of decreasing values, by the same convention we shall assign to the value t_m (which is the $(n - m + 1)$ away from the highest value) the probability

$$1 - \frac{n - m + 1}{n} = \frac{m - 1}{n} \quad (13)$$

Hence it is clear that the choice of a distribution-independent plotting position involves a certain arbitrariness and at the same time an ambiguity which can be resolved only where a criterion is specified for the most rational choice of position.

The problem has been tackled by Gumbel (Ref. 4, p. 29) who set some criteria for the purpose. They can be summed up as follows:

- a) the plotting position must be such that all the sample observations can be represented on the probability paper.

This criterion is not met by the positions m/n and $(m - 1)/n$, since a probability 1 corresponds to t_n in the first and a probability 0 to t_1 in the second. Furthermore, as the probability papers are constructed for unlimited variables, they do not contain the probability values 0 and 1.

An attempt to overcome this difficulty has been made by introducing the position

$$\frac{m - 1/2}{n} \quad (14)$$

the arithmetic mean of the two previous positions (mid-ranks). But this position, too, is not very satisfactory if tested with the following criterion:

b) the return period of a value equal to or greater than the largest observation (i.e., the number of trials needed on average to obtain a value greater than or equal to the largest observation) and the return period of a value smaller than the smallest observation (i.e., the number of trials needed on average to obtain a number smaller than the smallest observation) must tend to n , the number of observations. The return period is defined as the mean of the geometric distribution, relative to an event with probability p . Given an event with probability p at each test, the probability that it will occur for the first time at the v -th test will be

$$w(v) = pq^{v-1} \qquad q = 1 - p$$

The mean value of v is $\bar{v} = 1/p$ and represents the return period of the event with probability p .

Hence the return period of a value greater than or equal to the m -th value of an ordered sample is:

$$T_s(t_m) = \frac{1}{1 - \Phi(t_m)} \qquad (15)$$

So the return period of t_n , using position (14), is:

$$T_s(t_n) = \frac{1}{1 - \frac{n-1/2}{n}} = 2n \qquad (16)$$

which corresponds to an admission that an event t_n , which has occurred once in n trials, occurs on average once in every $2n$ trials. Similarly, considering the return period of a value smaller than t_1 , we have:

$$T_i(t_1) = \frac{1}{\Phi(t_1)} = 2n \qquad (17)$$

position (14) consequently gives an over-optimistic result precisely at the extreme values which, in many circumstances and in failure phenomena in particular, are the most significant ones. Moreover, the position m/n and $(m - 1)/n$ are not satisfactory from the standpoint of the return period; the return period of a value greater than or equal to t_m , for the position m/n , is:

$$T_s(t_m) = \frac{n}{n - m} \quad (18)$$

and is no longer defined for t_n , while the return period of a value smaller than t_m , for the position $(m - 1)/n$, is:

$$T_i(t_m) = \frac{n}{m - 1} \quad (19)$$

and is no longer defined for t_1 .

It is interesting now to consider, from the standpoint of the plotting position, the magnitudes discussed in Section 3 and defined on the basis of the distribution $\lambda_n(\tilde{\phi}_m)$ of the probabilities appropriate to the m -th value of an ordered sample.

The modal value

$$\tilde{\phi}_m = \frac{m-1}{n-1} \quad (20)$$

is not acceptable since it does not satisfy either the first or the second of the preceding criteria.

The median value $\check{\phi}_m$ defined by

$$\sum_{i=0}^{m-1} \binom{n}{i} \check{\phi}_m^i (1 - \check{\phi}_m)^{n-i} = 1/2 \quad (21)$$

satisfies the first criterion but not the second. The return period for t_n has the value

$$T_s(t_n) = \frac{1}{1 - \phi_n} \quad (22)$$

But from (21) we find $\phi_n = 2^{-1/n}$ and therefore, for high values of n ,

$$T_s(t_n) \approx 1.44 n \quad (23)$$

Also it can happen that $T_i(t_1) = T_g(t_n)$, so that the use of the median ranks as plotting position attributes to the extreme values a return period which exceeds n by 44% and therefore does not satisfy the second criterion.

Lastly, the mean of $\chi_n(\phi_m)$

$$\bar{\phi}_m = \frac{m}{n+1} \quad (24)$$

satisfies both criteria, at any rate for high values of n , since the return period for the extremes has the value $n + 1$.

This plotting position (mean ranks) appears to Gumbel (Ref. 4) to be the recommendable.

4.4 Least Squares Method

Let us briefly review the formulae expressing the distribution parameter estimates obtained by the least squares method. The values of the estimates are naturally different according to whether we minimize the deviations on the observed variable or on the reduced variable. It should be remarked that if the mean of the reduced variables y_m is used as plotting position, estimates free of systematic error will be obtained only by minimizing the deviations of the observed variable (Ref. 5, p. 198). With reference to (1) we then have:

$$A) \quad \sum_{1}^n (t-t_m)^2 = \min$$

$$\hat{\alpha}_A = \frac{\overline{ty} - \bar{t}\bar{y}}{\sigma_n^2} \quad \hat{\beta}_A = \bar{t} - \bar{y}/\hat{\alpha}_A \quad (25)$$

where

$$\bar{t} = \frac{1}{n} \sum_{m=1}^n t_m, \quad \bar{y} = \frac{1}{n} \sum_{m=1}^n y_m, \quad \overline{ty} = \frac{1}{n} \sum_{m=1}^n t_m y_m$$

$$\overline{y^2} = \frac{1}{n} \sum_{m=1}^n y_m^2 \quad \sigma_n^2 = \overline{y^2} - \bar{y}^2$$

Note that, the plotting position and distribution having been chosen, σ_n is a function of the sample size only.

$$\text{B) } \sum_{m=1}^n (y - y_m)^2 = \min$$

$$\frac{1}{\hat{\alpha}_B} = \frac{s_t^2}{\overline{ty} - \bar{t}\bar{y}} \quad \hat{\beta}_B = \bar{t} - \bar{y}/\hat{\alpha}_B \quad (26)$$

where

$$s_t^2 = (\overline{t^2} - \bar{t}^2) \frac{n}{n-1}$$

C) A third parameter estimate consists in minimizing the deviation of the points in parallel to a straight line determined by the condition $ty = 0$. The gradient of this line is equal and opposite to (1). In this case:

$$\frac{1}{\hat{\alpha}_C} = \left(\frac{1}{\hat{\alpha}_A \hat{\alpha}_B} \right)^{0.5} \quad (27)$$

$$\hat{\beta}_C = \bar{t} - \sqrt{(\bar{t} - \hat{\beta}_A)(\bar{t} - \hat{\beta}_B)}$$

If the observations are highly concentrated around (1), i.e., if the degree of correlation is high, the difference between the estimates obtained in the first two systems are small and the parameters estimated with the third system are roughly the arithmetic mean of the parameters estimated with the first two.

4.5 Building of Control Band

Having solved the fitting problem, i.e., determined the estimate values $\hat{\alpha}$, $\hat{\beta}$, our next task is to construct a control band on either side of the straight line $y = \hat{\alpha}(t - \hat{\beta})$, i.e., to delimit a zone within which, with a pre-established confidence level, we shall find the m -th observation of an ordered sample extractable from the population.

For this purpose the distribution of the m -th value of the sample, expressed by (5), must be taken into consideration. Naturally $\psi_n(t_m)$ is unknown, because $\phi(t_m)$ is unknown; on the other hand, $\theta_n(y_m)$ is known, since it is expressed by (9) as a function of the standard form $F(y_m)$. Furthermore, the two distributions are formally equal and hence the properties of the one that leave the parameters out of account are also properties of the other. In particular it has been shown (Ref. 4, p. 48) that the asymptotic form of (5), for central values of m , is normal with a mean value \bar{t}_m obtainable from:

$$\phi(\bar{t}_m) = \frac{m}{n+1} \quad (28)$$

and variance

$$\sigma^2(t_m) = \frac{\phi(\bar{t}_m)(1-\phi(\bar{t}_m))}{n \phi'^2(\bar{t}_m)} \quad (29)$$

If $\sigma^2(t_m)$ were known, then the control band problem would be solved, at least under the conditions for the validity of the asymptotic form. But $\sigma^2(t_m)$ is not known because it depends on $\phi'(\bar{t}_m)$. It is therefore necessary to use the preceding observation which also has an asymptotically normal distribution $\theta_n(y_m)$ with variance

$$\sigma^2(y_m) = \frac{F(\bar{y}_m)(1-F(\bar{y}_m))}{n F'^2(\bar{y}_m)} \quad (30)$$

which is independent of the α , β parameters and can only be calculated on the basis of the adopted distribution.

The standard error for the reduced variable y_m is therefore a pure number

$$\sqrt{n} \sigma(y_m) = \frac{\sqrt{F(1-F)}}{F'^2} \quad (31)$$

which can be determined, for each m , from the knowledge of $F(\bar{y}_m) = m/(n + 1)$ and also of $F'(\bar{y}_m)$ which can be found in the standard form tables beside $F(\bar{y}_m)$.

The standard error on t_m is then obtained from (1) and (31):

$$\sigma(t_m) = \frac{[\sqrt{n} \sigma(y_m)]}{\alpha \sqrt{n}} \quad (32)$$

and if α has been estimated, (32) can be used to construct the control curves. These will be obtained by connecting the points

$$\hat{t}_m \pm k\sigma(\hat{t}_m) \quad (33)$$

\hat{t}_m being a point on the estimated straight line and k a coefficient dependent on the degree of confidence attributed to the control band. For example, $k = 1.96$ expresses the probability 0.95 that for any m - within the limits of the hypothesis on the central values - the observation t_m of the generic sample lies within the interval $\hat{t}_m \pm 1.96 \sigma(\hat{t}_m)$. On these bases it is not possible to calculate the control band at the extreme values. As a rule one assumes that the foregoing considerations are valid in the probability interval 0.15 - 0.85. Outside that interval the asymptotic distribution of t_m ceases to be normal (Ref. 4, p. 49).

Another way of constructing control bands, which has the advantage of being independent of the standard form of the distribution adopted and of being valid even at the extreme sample

values, is the method which is mentioned at the end of Section 3 and is based on knowledge of the tabulated values of p for a certain confidence level $\eta(p)$.

5. APPLICATIONS

By way of example, three sets of data concerning times and breaking stresses of mechanical components are processed below by the methods we have described. One of the samples examined is incomplete, i.e., this is a case of failure times drawn from a sample which includes components still in operation; the other two samples are complete. The available data are processed with the KTEST code (Appendix 1) to establish which distribution interprets them best. Owing to the smallness of the samples, the Kolmogoroff test is ineffective in two cases because the level of significance reaches the max. value 1 in three out of the four distributions tried. For the third set, however, (stresses to failure) the test gives as the limit level of significance the values 97.6% for the Weibull distribution, 98.5% for the log-normal, and 97.5% for the normal and the exponential.

For greater simplicity and for the purposes of example, we shall assume, however, that the sets of data can be interpreted by a Weibull distribution, linearized as in expression (4), Section 4.

The scales of $(1 - R)$, R being the reliability, and of $Y = \log \ln 1/R$ are entered on the two horizontal axes of the relevant probability paper, whilst the observed variable and its logarithm are entered on the vertical axes.

5.1 Intermetallic Weld Failure Stresses

The following results were obtained from a series of shearing strength tests:

σ_i (kg/mm²)
 6.73 , 6.74 , 10.1 , 10.5 , 10.7 , 12.6 , 13.3 , 13.8
 14.7 , 14.75 , 15. , 15.5 , 16.3 , 16.7 , 17.1 , 17.2
 17.24 , 17.3 , 17.5 , 18.1 , 18.24 , 20.2 , 20.3 , 21.2
 21.9 , 22.6 , 23.1 , 24.5

Assuming a Weibull distribution and using the non-parametric method of mean ranks on probability paper, we obtain:

$$R(\sigma) = e^{-\left(\frac{\sigma}{19}\right)^3}$$

The maximum-likelihood method, however, gives:

$$R(\sigma) = e^{-\left(\frac{\sigma}{17.95}\right)^{4.13}}$$

Fig. 1 shows the two corresponding straight lines. The following table compares the strength values obtained with the two methods for given values of reliability R.

	$\sigma_{.95}$	$\sigma_{.99}$	$\sigma_{.9999}$
max. likelihood	8.7	5.88	1.93
mean ranks	7.2	4.2	0.89

If, however, we set a working strength of 6 kg/mm², the max. likelihood method gives a reliability value of .989 and a lower limit, with confidence level of 98%, given by

$$.989 - \sigma_R \zeta_{.95} = .975$$

where σ_R^2 is the reliability variance calculated from (31) in Section 2 ($\sigma_R^2 = 6.91 \cdot 10^{-5}$) and $\zeta_{.95}$ is the reduced normal variable at the 95% level.

Similarly, the non-parametric method gives a reliability value of .969 and a lower limit of .92 with confidence level 95%. The lower limit value is obtained by extrapolating the straight line which interpolates the 95% ranks calculated with the RANKS code.

5.2 Mechanical Seals on Pumps

A series of endurance tests yielded the following results:

t_1 (hours)

750, 900, 1018, 1200, 1250, 1500, 1500,

Assuming a Weibull distribution, we obtain the following expressions for the reliability:

a. with the max. likelihood method

$$R(t) = \exp \left(- \left(\frac{t}{1270} \right)^{5.09} \right)$$

b. with mean ranks plotting position on probability paper

$$R(t) = \exp \left(- \left(\frac{t}{1320} \right)^{3.5} \right)$$

c. with median ranks plotting position on probability paper

$$R(t) = \exp \left(- \left(\frac{t}{1300} \right)^{3.9} \right)$$

The corresponding straight lines are shown in Figs. 2 and 3. The table below gives the time-to-failure values with the three methods for set reliability values.

	max. likelihood	mean ranks	median ranks
$t_{.95}$	700	560	596
$t_{.99}$	515	355	400

On the other hand with a set mission time of 600 hours, the maximum-likelihood method gives a reliability value of .979 and the lower limit, with confidence level 95% is:

$$.979 - \sigma_R 1.65 = .932$$

where $\sigma_R^2 = 8.02 \cdot 10^{-4}$ is the variance of $R(600)$ calculated from (31), Section 2.

For $T = 600$ h the non-parametric methods give .954 (median ranks) and 0.937 (mean ranks). The lower limit, with confidence level 95%, calculated by extrapolating the 0.95 ranks, is .82.

5.3 Electromagnetic Valves

A set of twelve electromagnetic valves was reduced to six components in working order after a service of 3250 hours. The failure times of the eliminated components were:

t_i (hours)

1200, 1450, 2100, 2600, 3000, 3250

This sample cannot be treated by the maximum-likelihood method because the information contained in the fact that six valves are still working would be lost. With the non-parametric methods, however, this information can be taken into account and the reliability estimate is naturally different from what it would be if a sample of six were considered.

Again assuming a Weibull distribution, the use of probability papers gives a reliability estimate in accordance with the following expressions:

a. plotting with mean ranks

$$R(t) = \exp \left(- \left(\frac{t}{4300} \right)^{1.854} \right)$$

b. plotting with median ranks

$$R(t) = \exp \left(- \left(\frac{t}{4050} \right)^{2.23} \right)$$

represented in Figs. 4 and 5.

For set reliability values, the two estimates give the following values:

	mean ranks	median ranks
$t_{.95}$	900	1050
$t_{.99}$	357	510

5.4 Comments on the Results Obtained with the Various Methods

It emerges very clearly from the results that for the lower extreme values of the distribution

- the maximum-likelihood method gives more optimistic results than the median ranks method, which in turn gives more optimistic results than the mean ranks method;
- the difference between the results obtained with the various methods increases directly with the reliability sought and inversely with the Weibull distribution parameter α ;
- these differences in results are not tied to the sample size but rather depend on the statistical behaviour of the extreme values, which is evaluated differently with each method.

When, as in the case of mechanical components, the chief concern is to evaluate the extreme values, the use of the parametric method and probability papers offers advantages of greater simplicity than the classical maximum-likelihood method and also permits a far more realistic evaluation.

It amounts to obtaining a reliability estimate with a confidence level $A \geq 0.5$.

For, referring to (5), Section 3, and considering the first value of an ordered sample, we have:

$$\eta(p) = 1 - (1 - p)^n$$

or, calling the confidence level A and the reliability R :

$$A = 1 - R^n$$

This relation is graphed in Fig. 6 in respect of various values of n . The median rank relating to the lower end of the sample is obtained, for each n , from the intersection of the corresponding curve with the horizontal $A = 0.5$. If, however, the points corresponding to the reliability estimated with the mean rank are plotted on the curves, it will be seen that these estimates are equivalent to those obtained from (5), Section 3, for $A > 0.5$. If the maximum-likelihood estimates were plotted instead, one would find values for A smaller than 0.5. Another interesting consideration is that, in Fig. 6, the curves grow denser as n increases. This means that, given a certain value for the confidence level A , the reliability gain in the extreme sample value is progressively slighter as n increases; hence one could evaluate a maximum sample size such that trials on bigger samples would not introduce significant improvements in the reliability values.

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APPENDIX 1 - Description of KTEST code

With reference to Section 2.3.2, the KTEST code, written in FORTRAN H for IBM 360/65, performs the Kolmogoroff test on the Weibull, normal, log-normal and exponential distributions. The estimated distributions are determined from the sample data by the method of probability papers, i.e., the fitting to the data is done with the linearized form of the distribution (Section 4), after each sample value has been assigned its appropriate probability according to the non-parametric method selected.

The code performs the following operations:

- a) It defines the regression variables for each of the distributions studied and calculates their values to correspond with the sample data.
- b) It performs the fitting by the least-squares method (minimizing the deviations of the measured variable) and then determines an estimate of the parameters of each distribution.
- c) It calculates the cumulative probabilities appropriate to the sample values, using the estimated distribution.
- d) It performs the Kolmogoroff test, comparing the calculated probabilities and those assigned to the sample values by the non-parametric method adopted.

The regression variables x_i , y_i are defined as follows, t_i being the i -th value of the ordered sample and P_i the probability value attributed to t_i :

1. Weibull distribution

$$x_i = \log t_i \qquad y_i = \log \ln \frac{1}{1 - P_i}$$

with reference to (4), Section 4.2.

2. Normal distribution

$$x_i = t_i \quad y_i \text{ obtained by solving the equation}$$

$$\frac{1}{\sqrt{\pi}} \int_0^{y_i} e^{-\eta^2} d\eta + 0.5 - P_i = 0$$

3. Log-normal distribution

$$x_i = \log t_i \quad y_i \text{ as for the normal distribution}$$

4. Exponential distribution

$$x_i = t_i \quad y_i = \log \frac{1}{1 - P_i}$$

The regression in every case is of the form $y = \alpha(x - \beta)$. The coefficients α, β , tied to the distribution parameters, are determined by the least-squares method.

In applying the test the boundary level of significance is determined for each distribution, i.e., the level that constitutes the upper limit of the probability with which the distribution hypothesis can be accepted. Hence the data are interpreted best from the distribution that has the highest boundary level of significance. Referring to Section 2.3.2, this level is given by

$$\alpha = 1 - Q(\lambda)$$

where $\lambda = D_n \sqrt{n}$ and $Q(\lambda)$ is the function (12).

Subprogrammes employed:

1. FUNCTION ZERO(A1, B1, P, PREC)

Calculates by the bisection method the regression variable y in the case of normal or log-normal distribution. A1, B1 are the limits of the interval containing the desired radix

(A1 = -3, B1 = 3), P is the value of the non-parametric estimate, PREC is the precision with which y is obtained.

2. FUNCTION DMAX(A,K)

Calculates the largest of the values (all positive) of a matrix A of K dimensions. It is used to determine D_n , the maximum difference between the calculated probability and that attributed to the generic value of the sample.

3. FUNCTION Q(Y)

Calculates the value of the asymptotic distribution of $D_n \sqrt{n}$, for a given Y, with reference to (12) of Section 2.3.2.

This subprogramme is supplied by the IBM library under the name of SUBROUTING SMIRN. Reference should be made to the library for a description of the method employed.

Input data

N	Sample size (max 40)
ND	Number of distributions examined
VITA(J)	Matrix of sample values
PR(J)	Matrix of probability values attributed to the sample values

CCCCCCCC

QUESTO PROGRAMMA ESEGUE IL TEST DI KOLMOGOROV SU DIVERSE DISTRIB. STATISTICHE CHE VENGONO STIMATE, A PARTIRE DAI DATI DEL CAMPIONE, ESEGUENDO IL FITTING CON LE FORME LINEARIZZATE- VIENE COSI DETERMINATA LA DISTRIBUZIONE CHE MEGLIO SI ADATTA AI VALORI DEL CAMPIONE-

ISN 0002
ISN 0003
ISN 0004
ISN 0005
ISN 0006
ISN 0007
ISN 0008
ISN 0009
ISN 0010
ISN 0011
ISN 0012

```
DIMENSION VITA(40),PR(40),X(40),Y(40),VRD(40),D(40),CLL(10),PRC(40)
1)
READ (5,1) N,ND
1 FORMAT (2I3)
READ (5,2) (VITA(J),J=1,N)
2 FORMAT (8E10.5)
READ (5,3) (PR(J),J=1,N)
3 FORMAT (8E10.5)
WRITE (6,4)
4 FORMAT (//30X'FITTING A DISTRIBUZIONE DI WEIBULL')
WRITE (6,5)
5 FORMAT (///10X'J',7X'VITA(J)',8X'PR(J)',11X'X(J)',11X'Y(J)',9X'PRC
1(J)',11X'D(J)')//)
```

CCC

DEFINIZIONE VARIAB. REGR. PER DISTRIB. DI WEIBULL

ISN 0013
ISN 0014
ISN 0015
ISN 0016
ISN 0017

```
I=0
10 DO 100 J=1,N
X(J)=ALOG10(VITA(J))
100 Y(J)=ALOG10(ALOG(1./(1.-PR(J))))
GO TO 2000
```

CCCC

DEFINIZ. VARIAB. REGR. PER DISTRIB. LOG-NORMALE
X(J) COME IN DO 100

ISN 0018
ISN 0019
ISN 0020
ISN 0021
ISN 0022
ISN 0023

```
2J DO 200 J=1,N
200 Y(J)=ZERO(-3.,3.,PR(J),1.E-4)
WRITE (6,11)
11 FORMAT (//30X'FITTING A DISTRIBUZ. LOG. NORMALE')
WRITE (6,5)
GO TO 2000
```

CCCC

DEFINIZ. VARIAB. REGR. PER DISTRIB. NORMALE
Y(J) COME IN DO 200

ISN 0024
ISN 0025
ISN 0026
ISN 0027
ISN 0028

```
30 DO 300 J=1,N
300 X(J)=VITA(J)
WRITE (6,12)
12 FORMAT (//30X'FITTING A DISTRIBUZ. NORMALE')
WRITE (6,5)
```

ISN 0029

GO TO 2000

CCCC

DEFINIZ. VARIAB. REGR. PER DISTRIB. ESPONENZIALE
X(J) COME IN DO 300

ISN 0030
ISN 0031
ISN 0032
ISN 0033
ISN 0034
ISN 0035

40 DO 400 J=1,N
400 Y(J)=ALOG(1./((1.-PR(J))))
WRITE (6,13)
13 FORMAT (7/30X,'FITTING A DISTRIBUZ. ESPONENZIALE')
WRITE (6,5)
GO TO 2000

CCCC

CALCOLO COEFF. REGRESSIONE LINEARE Y=ALFA*(X-BETA)
DEVIAZ. QUADR. MIN IN DIREZ. X

ISN 0036
ISN 0037
ISN 0038
ISN 0039
ISN 0040
ISN 0041
ISN 0042
ISN 0043
ISN 0044
ISN 0045
ISN 0046
ISN 0047
ISN 0048
ISN 0049
ISN 0050
ISN 0051

2000 SXY=0.
SX=0.
SY=0.
SY2=0.
DO 2001 J=1,N
SXY=SXY+X(J)*Y(J)
SX=SX+X(J)
SY=SY+Y(J)
2001 SY2=SY2+Y(J)**2
Z=N
2002 ALFA=(Z*SY2-SY**2)/(Z*SXY-SX*SY)
2003 BET=SX-SY/ALFA
BETA=BET/Z
IF (I) 210,210,209
209 CONTINUE
GO TO (220,230,240),I

CCCC

CALCOLO PROB. CON DISTRIB. DI WEIBULL STIMATA

ISN 0052
ISN 0053
ISN 0054
ISN 0055
ISN 0056
ISN 0057
ISN 0058
ISN 0059
ISN 0060
ISN 0061
ISN 0062

210 B=10.**BETA
DO 215 J=1,N
PRC(J)=1.-1./EXP((VITA(J)/B)**ALFA)
215 D(J)=ABS(PR(J)-PRC(J))
WRITE (6,6) (J,VITA(J),PR(J),X(J),Y(J),PRC(J),D(J),J=1
6 FORMAT (8X,I3,6E15.5)
DMX=DMAX(D,N)
WRITE (6,14) DMX
14 FORMAT (78X,'DMX=' F15.5)
FN=FLOAT(N)
TETA=DMX*SQRT(FN)

```

ISN 0063      CLL(1)=1.-Q(TETA)
ISN 0064      WRITE (6,7) ALFA,BETA
ISN 0065      7 FORMAT (//3X'I COEFF. DELLA REGRESSIONE SONO ALFA='E15.5,3X'BETA='
              1'E15.5)
ISN 0066      WRITE (6,8) CLL(1)
ISN 0067      8 FORMAT (//3X'IL LIVELLO DI CONF. LIMITE SECONDO IL TEST DI KOLMOG'
              1'ROV E''='F15.5)
ISN 0068      I=I+1
ISN 0069      GO TO 20

```

C
C
C
C

CALCOLO PROB. CON DISTRIB. LOG-NORMALE STIMATA

```

ISN 0070      220 DO 225 J=1,N
ISN 0071      VRD(J)=ALFA+(ALOG10(VITA(J))-BETA)
ISN 0072      221 PRC(J)=0.5+0.5*ERF(VRD(J))
ISN 0073      225 D(J)=ABS(PRC(J)-PRC(J))
ISN 0074      WRITE (6,6) (J,VITA(J),PR(J),X(J),Y(J),PRC(J),D(J),J=1,N)
ISN 0075      DMX=DMAX(D,N)
ISN 0076      WRITE (6,14) DMX
ISN 0077      FN=FLOAT(N)
ISN 0078      TETA=DMX*SQRT(FN)
ISN 0079      CLL(2)=1.-Q(TETA)
ISN 0080      WRITE (6,7) ALFA,BETA
ISN 0081      WRITE (6,8) CLL(2)
ISN 0082      I=I+1
ISN 0083      GO TO 30

```

C
C
C
C

CALCOLO PROB. CON DISTRIB. NORMALE STIMATA

```

ISN 0084      230 DO 235 J=1,N
ISN 0085      VRD(J)=ALFA*(VITA(J)-BETA)
ISN 0086      231 PRC(J)=0.5+0.5*ERF(VRD(J))
ISN 0087      235 D(J)=ABS(PRC(J)-PRC(J))
ISN 0088      WRITE (6,6) (J,VITA(J),PR(J),X(J),Y(J),PRC(J),D(J),J=1,N)
ISN 0089      DMX=DMAX(D,J)
ISN 0090      WRITE (6,14) DMX
ISN 0091      FN=FLOAT(N)
ISN 0092      TETA=DMX*SQRT(FN)
ISN 0093      CLL(3)=1.-Q(TETA)
ISN 0094      WRITE (6,7) ALFA,BETA
ISN 0095      WRITE (6,8) CLL(3)
ISN 0096      I=I+1
ISN 0097      GO TO 40

```

C
C
C

CALCOLO PROB. CON DISTRIB. EXP. STIMATA

```

C
ISN 0098 240 DO 245 J=1,N
ISN 0099   VRO(J)=ALFA*(VITA(J)-BETA)
ISN 0100   PRC(J)=1.-1./EXP(VRO(J))
ISN 0101 245 D(J)=ABS(PR(J)-PRC(J))
ISN 0102   WRITE (6,6) (J,VITA(J),PR(J),X(J),Y(J),PRC(J),D(J),J=1,N)
ISN 0103   DMX=DMAX(D,N)
ISN 0104   WRITE (6,14) DMX
ISN 0105   FN=FLUAT(N)
ISN 0106   TETA=DMX*SQRT(FN)
ISN 0107   CLL(4)=1.-Q(TETA)
ISN 0108   WRITE (6,7) ALFA,BETA
ISN 0109   WRITE (6,3) CLL(4)
ISN 0110   CLMX=DMAX(CLL,N)
ISN 0111   WRITE (6,9) CLMX
ISN 0112 9  FORMAT (//8X'LA DISTRIB. CHE MEGLIO INTERPRETA IL CAMPIONE E''QUE
          1LLA CON CLL='E15.5)
ISN 0113   STOP
ISN 0114   END

```

```
ISN 0002      C      FUNCTION PHAX(A,K)
ISN 0003      C      DIMENSION A(1)
ISN 0004      C      X=A(1)
ISN 0005      C      DO 3 I=2,K
ISN 0006      C      IF(A(I).LE.X) GO TO 3
ISN 0008      C      X=A(I)
ISN 0009      C      3 CONTINUE
ISN 0010      C      DMAX=X
ISN 0011      C      RETURN
ISN 0012      C      END
```

```
ISN 0002      C      FUNCTION ZERO(A1,B1,P,PREC)
ISN 0003      C      A=A1
ISN 0004      C      B=B1
ISN 0005      C      1 IF(ABS(A-B)-PREC)2,2,3
ISN 0006      C      3 C=0.5*(A+B)
ISN 0007      C      PP=0.5-P
ISN 0008      C      4 W=0.5*ERF(A)+PP
ISN 0009      C      5 U=0.5*ERF(C)+PP
ISN 0010      C      IF(U*N)6,7,3
ISN 0011      C      6 B=C
ISN 0012      C      GO TO 1
ISN 0013      C      8 A=C
ISN 0014      C      GO TO 1
ISN 0015      C      7 ZERO=C
ISN 0016      C      GO TO 9
ISN 0017      C      2 ZERO=A
ISN 0018      C      9 RETURN
ISN 0019      C      END
```

```
ISN 0002      C      FUNCTION Q(Y)
ISN 0003      C      IF(Y-.27)1,1,2
ISN 0004      C      1 Q=0.0
ISN 0005      C      GO TO 9
ISN 0006      C      2 IF(Y-1.0)3,6,6
ISN 0007      C      3 Q1=EXP(-1.233701/Y**2)
ISN 0008      C      Q2=Q1*Q1
ISN 0009      C      Q4=Q2*Q2
ISN 0010      C      Q3=Q4*Q4
ISN 0011      C      IF(Q3-1.0E-25)4,5,5
ISN 0012      C      4 Q3=0.0
ISN 0013      C      5 Q=(2.506628/Y)*Q1*(1.0+Q8*(1.0+Q8*Q8))
ISN 0014      C      GO TO 9
ISN 0015      C      6 IF(Y-3.1)8,7,7
ISN 0016      C      7 Y=1.0
ISN 0017      C      GO TO 9
ISN 0018      C      8 Q1=EXP(-2.0*Y*Y)
ISN 0019      C      Q2=Q1*Q1
ISN 0020      C      Q4=Q2*Q2
ISN 0021      C      Q8=Q4*Q4
ISN 0022      C      Q=1.0-2.0*(Q1-Q4+Q8*(Q1-Q8))
ISN 0023      C      9 RETURN
ISN 0024      C      END
```


APPENDIX 2 - Description of VITA code

With reference to Section 2.5.2 of the text, the VITA code programmed in FORTRAN H for IBM 360/65 performs the following operations:

- a) It estimates the shape and scale parameters, α, λ of the incomplete Weibull distribution.
- b) It calculates the estimate variances $\hat{\alpha}, \hat{\lambda}$, inverting the matrix (29) and making use of (5).
- c) It calculates the reliability value at a given mission time.
- d) It calculates the reliability variance, making use of relation (31).
- e) It tabulates the estimated Weibull distribution and its probability density.

As regards a) above, we may note that the resolving equation is as follows:

$$\hat{\alpha} = \frac{n \sum_i t_i^{\hat{\alpha}}}{n \sum_i t_i^{\hat{\alpha}} \log t_i - \sum_i t_i^{\hat{\alpha}} \sum_i \log t_i} \quad (\text{A2.1})$$

obtained by substituting (26) in (27).

The value for $\hat{\alpha}$ that starts the iteration is obtained from (28),

equivalent to $\log \frac{\sum_i t_i^{\alpha}}{n}$

$$\alpha = \frac{\log \frac{\sum_i t_i^{\alpha}}{n}}{\log \frac{m}{\Gamma(1+1/\alpha)}} \quad (\text{A2.2})$$

m being the sample mean.

Both (A2.1) and (A2.2) are equations of the type $\zeta = f(\zeta)$ which can be solved by an iteration process represented by the formula (Ref. 1, p. 184)

$$\zeta_0^1 = \zeta_0 + \frac{(\zeta_1 - \zeta_0)^2}{2\zeta_1 - \zeta_0 - \zeta_2} \quad (\text{A2.3})$$

where ζ_0 is a trial initial value, $\zeta_1 = f(\zeta_0)$, $\zeta_2 = f(\zeta_1)$ and ζ_0^1 the initial value for the second iteration. The process usually converges very fast, if $f'(\bar{\zeta}) \neq 1$ where $\bar{\zeta}$ is the desired radix, because the error for each successive iteration is an infinitesimal of higher order than the one in the preceding iteration.

Subprogrammes employed:

1. FUNCTION TETA(A) calculates $\sum_1 t_1^\alpha$
2. FUNCTION STAR1(A) calculated the function (A2.2)
3. FUNCTION STAR2(A) calculates the function (A2.1)
4. FUNCTION ZERO(Y, STAR, PREC) carries out the iteration according to (A2.3) on the generic function STAR, where Y is the trial initial value. It stops the process when the result of the difference in the values of two successive iterations is smaller than PREC, i.e., than the set precision value.

Input data:

N	Sample size
A1	Initial value for the iteration on (A2.2)
PREC	Precision of iteration process
NOIT	Limit number of iterations permitted
T	Mission time
TB	Control indicator to effect (TB \neq 0) or not effect (TB = 0) tabulation of the distribution values
VITA(J)	Is the whole of the sample values, for J = 1, ..., N

```

C      PROGRAMMA PRINCIPALE
C
ISN 0002  DIMENSION TM(100),P(100),PP(100),S(100),Z(100)
ISN 0003  COMMON/PIPPQ/VITA(100)//N,J,B,NOIT
C
ISN 0004  READ(5,1)N,A1,PREC,NOIT,T,TR
ISN 0005  1 FORMAT (I2,2E0.2,I4,E9.2,I2)
ISN 0006  READ (5,2) (VITA(J),J=1,N)
ISN 0007  2 FORMAT (6E10.3)
ISN 0008  WRITE (5,100)
ISN 0009  100 FORMAT (30X'DATI DI PARTENZA'///)
ISN 0010  WRITE (6,101)
ISN 0011  101 FORMAT (10X'TEMPI DI VITA'//)
ISN 0012  WRITE (6,102) (J,VITA(J),J=1,N)
ISN 0013  102 FORMAT (10X,I5,E13.4)
ISN 0014  WRITE (6,103) A1,PREC
ISN 0015  103 FORMAT (//10X'A1='E9.2,3X,'PREC='E9.2///)
C
C      VALORE DI PRIMO TENTATIVO
C
ISN 0016  N=N
ISN 0017  J=J
ISN 0018  EXTERNAL STAR1
ISN 0019  CO=ZERO(A1,STAR1,PREC)
ISN 0020  IF(CO) 10,10,15
ISN 0021  15 CONTINUE
ISN 0022  WRITE (6,104)
ISN 0023  104 FORMAT (35X'RISULTATI'//)
ISN 0024  WRITE (6,105) CO,B
ISN 0025  105 FORMAT (10X'CO='F12.4,3X,'NO ITERAZIONI PER CO='F4.0//)
ISN 0026  WRITE (6,106)
ISN 0027  106 FORMAT (15X'PARAMETRI WEIBULL'//)
C
C      WEIBULL SHAPE PARAMETER ALFA
C
ISN 0028  EXTERNAL STAR2
ISN 0029  ALFA=ZERO(CO,STAR2,PREC)
C
C      WEIBULL SCALE PARAMETER AMDA
C
ISN 0030  AN=N
ISN 0031  TI=TETA(ALFA)
ISN 0032  AMDA=AN/TI
ISN 0033  WRITE (6,107) ALFA,B,AMDA
ISN 0034  107 FORMAT (5X'ALFA='E12.3,2X'NO ITERAZ. PER ALFA='F3.0,2X'AMDA='E12.3
1)
C
C      CALCOLO MATRICE COVARIANZA

```

```

ISN 0035      SL1=0
ISN 0036      SL2=0
ISN 0037      DO 30 J=1,N
ISN 0038      S(J)=VITA(J)**ALFA*(ALOG(VITA(J)))**2
ISN 0039      SL1=SL1+S(J)
ISN 0040      Z(J)=VITA(J)**ALFA*ALOG(VITA(J))
ISN 0041      30 SL2=SL2+Z(J)
ISN 0042      31 F1=-AN/ALFA**2-AMDA*SL1
ISN 0043      32 F2=-AN/AMDA**2
ISN 0044      33 F12=-SL2
ISN 0045      34 DET=F1*F2-F12**2
ISN 0046      IF(DET)35,39,35
ISN 0047      35 VAR1=-F2/DET
ISN 0048      36 VAR2=-F1/DET
ISN 0049      37 CVR12=F12/DET
ISN 0050      WRITE (6,38) VAR1,VAR2,CVR12
ISN 0051      38 FORMAT (/5X'VAR.ALFA='E12.3,2X'VAR.AMDA='E12.3,2X'CVR.ALFA-AMDA='
ISN 0052      1E12.3//)
ISN 0053      GO TO 41
ISN 0054      39 WRITE (6,40)
ISN 0055      40 FORMAT (/5X'DETERMINANTE=0')
C
C
C
C
ISN 0055      41 R=1./EXP(AMDA*T**ALFA)
ISN 0056      42 VR1=T**(2.*ALFA)/EXP(2.*AMDA*T**ALFA)
ISN 0057      43 VR2=AMDA**2*ALOG(T)**2*VAR1+VAR2+2.*AMDA*ALOG(T)*CVR12
ISN 0058      44 VARR=VR1*VR2
ISN 0059      WRITE (6,45) T,R,VARR
ISN 0060      45 FORMAT (/5X'PER T='F9.3,2X'LA RELIABILITY E='F9.5,2X'LA SUA VARI
C
C
C
C
ISN 0061      46 IF(TB)46,11,46
ISN 0062      TMX=2.*VITA(N)
ISN 0063      TMIN=0.1*VITA(1)
ISN 0064      TM(1)=TMIN
ISN 0065      DO 50 K=1,99
ISN 0066      TM(K+1)=TM(K)+(TMX-TMIN)/99.
ISN 0067      P(K)=1.-1./EXP(AMDA*TM(K)**ALFA)
ISN 0068      50 PP(K)=AMDA*ALFA*(TM(K)**(ALFA-1.))*(1-P(K))
ISN 0069      WRITE (6,108)
ISN 0070      108 FORMAT (/30X'TABULAZIONE WEIBULL'//)
ISN 0071      WRITE (6,109) (TM(K),P(K),PP(K),K=1,100)
ISN 0072      109 FORMAT (5X,E16.3,E23.4,E23.4)
ISN 0073      GO TO 11
ISN 0074      10 WRITE (6,9)
ISN 0075      9 FORMAT (3X'PRIMA ITERAZ. NON CONV.')
ISN 0076      11 STOP

```

```
ISN 0002      FUNCTION TETA(A)
ISN 0003      DIMENSION T(100)
ISN 0004      COMMON/PIPP0/VITA(100)//N,J
ISN 0005      TETA=0
ISN 0006      DO 10 J=1,N
ISN 0007      T(J)=VITA(J)**A
ISN 0008      10 TETA=TETA+T(J)
ISN 0009      RETURN
ISN 0010      END
```

```
ISN 0002      FUNCTION STAR1(A)
ISN 0003      COMMON/PIPP0/VITA(100)//N,J
ISN 0004      TI=TETA(A)
ISN 0005      AN=N
ISN 0006      TETA1=ALOG(TI/AN)
ISN 0007      SM=0
ISN 0008      DO 10 J=1,N
ISN 0009      10 SM=SM+VITA(J)
ISN 0010      EDIA=SM/AN
ISN 0011      X=1.+1./A
ISN 0012      TETA2=ALOG(EDIA/GAMMA(X))
ISN 0013      STAR1=TETA1/TETA2
ISN 0014      RETURN
ISN 0015      END
```

```
ISN 0002      FUNCTION STAR2(A)
ISN 0003      COMMON/PIPP0/VITA(100)//N,J
ISN 0004      DIMENSION S(100),Z(100)
ISN 0005      TI=TETA(A)
ISN 0006      AN=N
ISN 0007      TETA3=AN*TI
ISN 0008      SL=0
ISN 0009      DO 10 J=1,N
ISN 0010      S(J)=VITA(J)**A*ALOG(VITA(J))
ISN 0011      10 SL=SL+S(J)
ISN 0012      TETA4=AN*SL
ISN 0013      SZ=0
ISN 0014      DO 20 J=1,N
ISN 0015      Z(J)=ALOG(VITA(J))
ISN 0016      20 SZ=SZ+Z(J)
ISN 0017      TETA5=SZ*TI
ISN 0018      TETA6=TETA4-TETA5
ISN 0019      STAR2=TETA3/TETA6
ISN 0020      RETURN
ISN 0021      END
```

```
ISN 0002      FUNCTION ZERO(Y,STAR,PREC)
ISN 0003      COMMON N,J,B,NOIT
ISN 0004      B=0
ISN 0005      5 C1=Y
ISN 0006      6 X1=STAR(C1)
ISN 0007      IF(ABS(X1-C1)-PREC)10,10,20
ISN 0008      20 X2=STAR(X1)
ISN 0009      21 C2=C1+(X1-C1)**2/(2.*X1-C1-X2)
ISN 0010      C1=C2
ISN 0011      B=B+1
ISN 0012      IF(B-NOIT)6,12,12
ISN 0013      12 ZERO=0
ISN 0014      10 ZERO=X1
ISN 0015      RETURN
ISN 0016      END
```

APPENDIX 3 - Description of RANKS code⁽¹⁾

With reference to Section 3.2.3, the RANKS code, written in FORTRAN H for IBM 360/65, solves the following equation in p:

$$1-\eta(p) - \sum_{i=0}^{m-1} \binom{n}{i} p^i (1-p)^{n-i} = 0 \quad (A3.1)$$

for given values of $\eta(p)$, n , m , and all values of i between 0 and $m-1$. The bisection method is used for the solution.

Subprogrammes employed:

1. FUNCTION PIPPO(Z) calculates the function (A3.1)
2. FUNCTION ZERO(A1, B1, Y, PREC) applies the bisection method to the Y function to find the Y radix in the interval A1, B1 with precision PREC.

Input data:

AI(K) values of confidence level $\eta(p)$ for $K = 1, 2, 3$

Remarks:

- the sample dimensions must be ≤ 40
- the precision of the bisection method is $5 \cdot 10^{-5}$
- A1 = 0, B1 = 1

(1) The original version of the code, in F2V3 on IBM 7090, is given in Ref. 12.

TABLE 1 - 0.05 RANKS

		Sample size = n																		
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
1	.0500	.0253	.0169	.0127	.0102	.0085	.0073	.0064	.0057	.0051	.0045	.0042	.0039	.0036	.0034	.0032	.0030	.0028	.0027	.0025
2		.2236	.1353	.0976	.0764	.0628	.0534	.0464	.0410	.0367	.0333	.0305	.0280	.0250	.0242	.0227	.0213	.0201	.0190	.0180
3			.3684	.2486	.1892	.1531	.1288	.1111	.0977	.0872	.0788	.0719	.0650	.0611	.0568	.0531	.0499	.0470	.0445	.0421
4				.4729	.3426	.2713	.2253	.1929	.1687	.1500	.1351	.1228	.1126	.1040	.0957	.0902	.0846	.0797	.0753	.0713
5					.5493	.4182	.3412	.2892	.2513	.2224	.1996	.1810	.1656	.1527	.1417	.1321	.1237	.1164	.1099	.1041
6						.6069	.4793	.4003	.3449	.3035	.2712	.2453	.2239	.2061	.1909	.1778	.1664	.1563	.1475	.1395
7							.6518	.5293	.4503	.3934	.3458	.3152	.2870	.2635	.2437	.2267	.2119	.1989	.1875	.1773
8								.6877	.5709	.4921	.4356	.3908	.3548	.3250	.3000	.2786	.2601	.2440	.2297	.2170
9									.7169	.6058	.5299	.4727	.4274	.3904	.3596	.3334	.3108	.2912	.2739	.2586
10										.7411	.6356	.5619	.5053	.4600	.4225	.3910	.3640	.3406	.3201	.3019
11											.7616	.6513	.5699	.5343	.4992	.4616	.4397	.4192	.3981	.3769
12												.7791	.6837	.6146	.5602	.5156	.4781	.4460	.4181	.3936
13													.7942	.7032	.6365	.5834	.5394	.5022	.4700	.4420
14														.8073	.7206	.6562	.6043	.5611	.5242	.4922
15															.8189	.7360	.6738	.6233	.5809	.5444
16																.8292	.7498	.6897	.6406	.5990
17																	.8384	.7623	.7042	.6563
18																		.8467	.7736	.7174
19																			.8541	.7839
20																				.8609

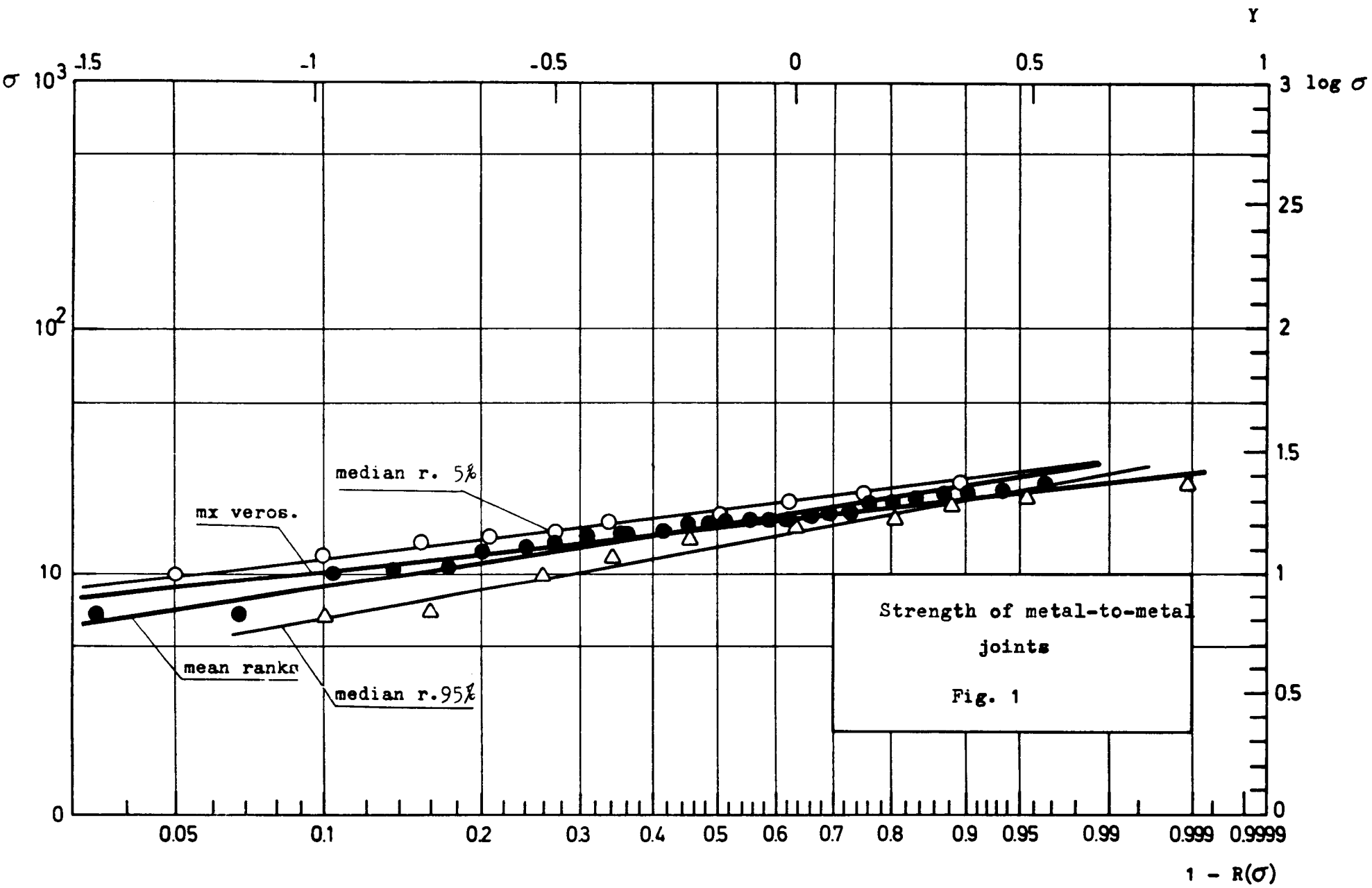
TABLE 2 - 0.5 RANKS

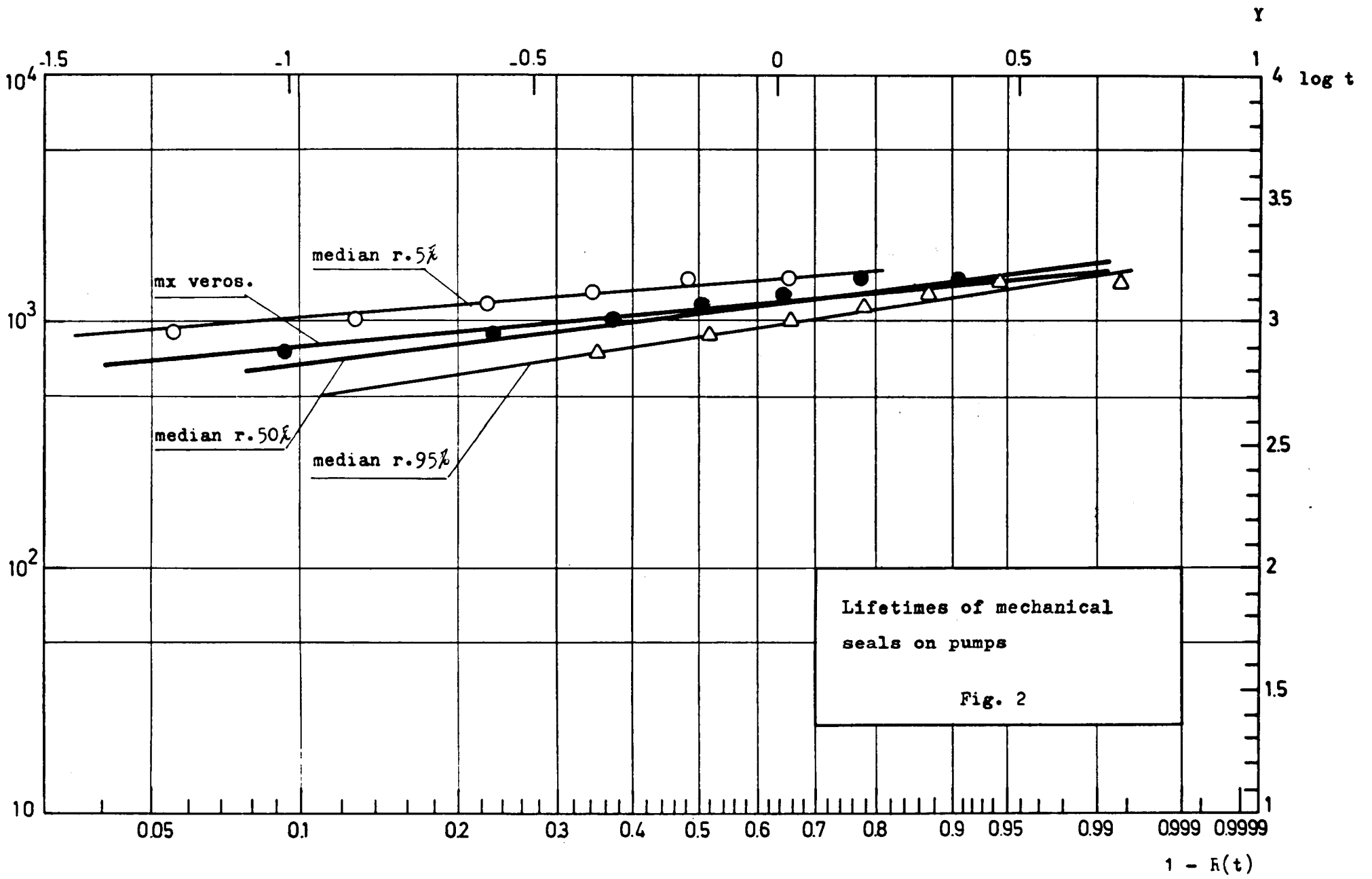
	Sample size - N																			
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
1	.5000	.2929	.2063	.1591	.1294	.1091	.0943	.0830	.0741	.0670	.0611	.0561	.0519	.0483	.0451	.0424	.0399	.0377	.0358	.0341
2		.7071	.5000	.3857	.3138	.2644	.2285	.2011	.1796	.1623	.1479	.1360	.1258	.1170	.1094	.1027	.0968	.0915	.0868	.0825
3			.7937	.6143	.5000	.4214	.3641	.3205	.2862	.2585	.2358	.2167	.2004	.1865	.1043	.1636	.1542	.1458	.1382	.1315
4				.8409	.6862	.5786	.5000	.4402	.3931	.3551	.3238	.2975	.2753	.2561	.2394	.2247	.2118	.2002	.1899	.1805
5					.8705	.7355	.6359	.5598	.5000	.4517	.4119	.3785	.3502	.3257	.3045	.2859	.2694	.2547	.2415	.2296
6						.8909	.7715	.6795	.6069	.5483	.5000	.4595	.4250	.3954	.3697	.3470	.3270	.3092	.2932	.2788
7							.9057	.7989	.7137	.6449	.5881	.5405	.5000	.4651	.4348	.4082	.3847	.3637	.3449	.3279
8								.9170	.8204	.7414	.6762	.6215	.5749	.5349	.5000	.4694	.4423	.4182	.3966	.3771
9									.9259	.8377	.7642	.7024	.6498	.6046	.5652	.5306	.5000	.4727	.4483	.4262
10										.9330	.8520	.7833	.7247	.6742	.6303	.5918	.5576	.5273	.5000	.4754
11											.9389	.8640	.7995	.7439	.6955	.6529	.6153	.5818	.5517	.5246
12												.9438	.8742	.8135	.7606	.7141	.6729	.6363	.6034	.5737
13													.9481	.8830	.8257	.7752	.7306	.6908	.6551	.6229
14														.9517	.8906	.8363	.7882	.7453	.7068	.6720
15															.9548	.8973	.8458	.7997	.7585	.7212
16																.9576	.9032	.8542	.8101	.7703
17																	.9600	.9085	.8617	.8194
18																		.9622	.9132	.8685
19																			.9642	.9175
20																				.9659

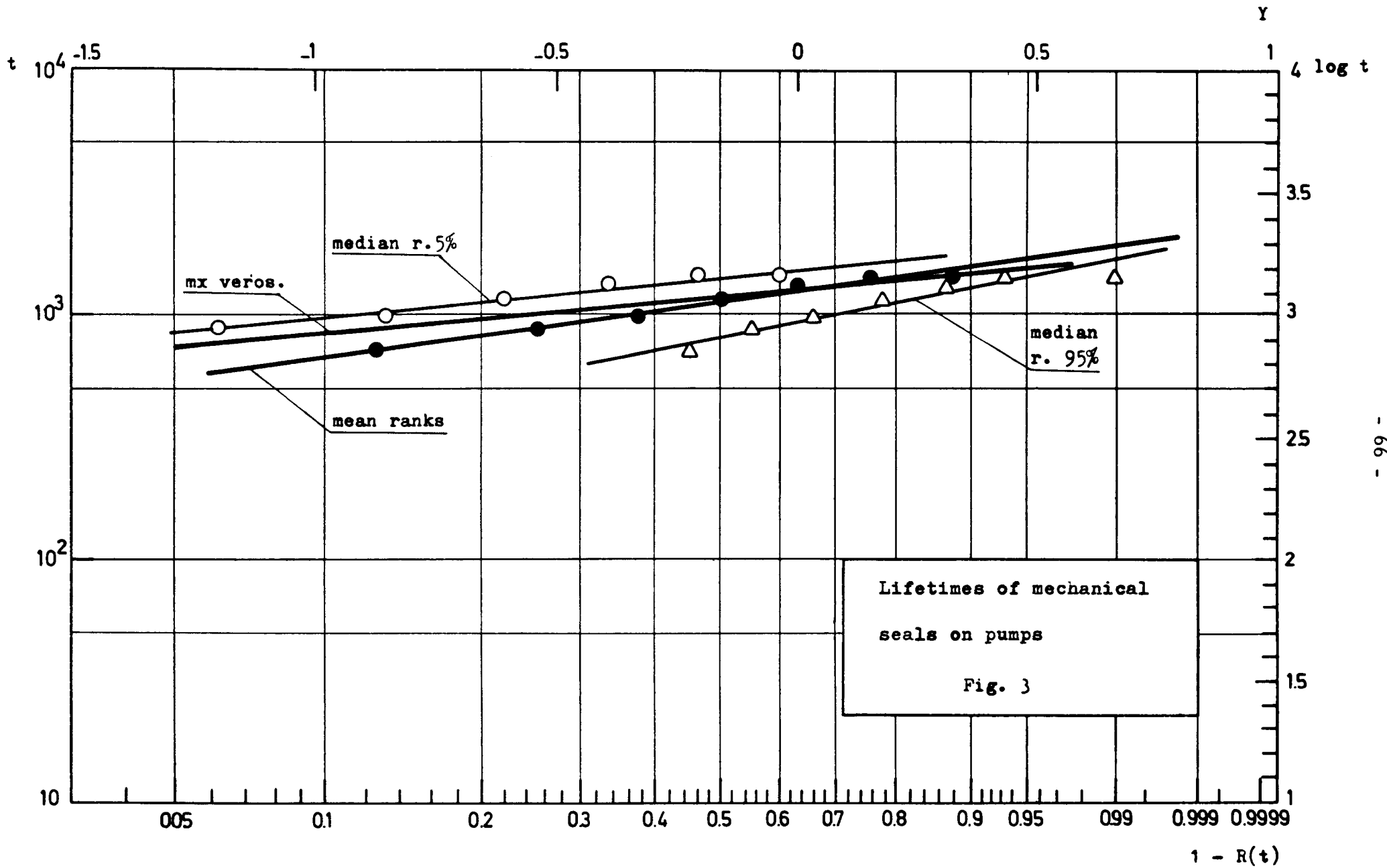
TABLE 3 - 0.95 RANKS

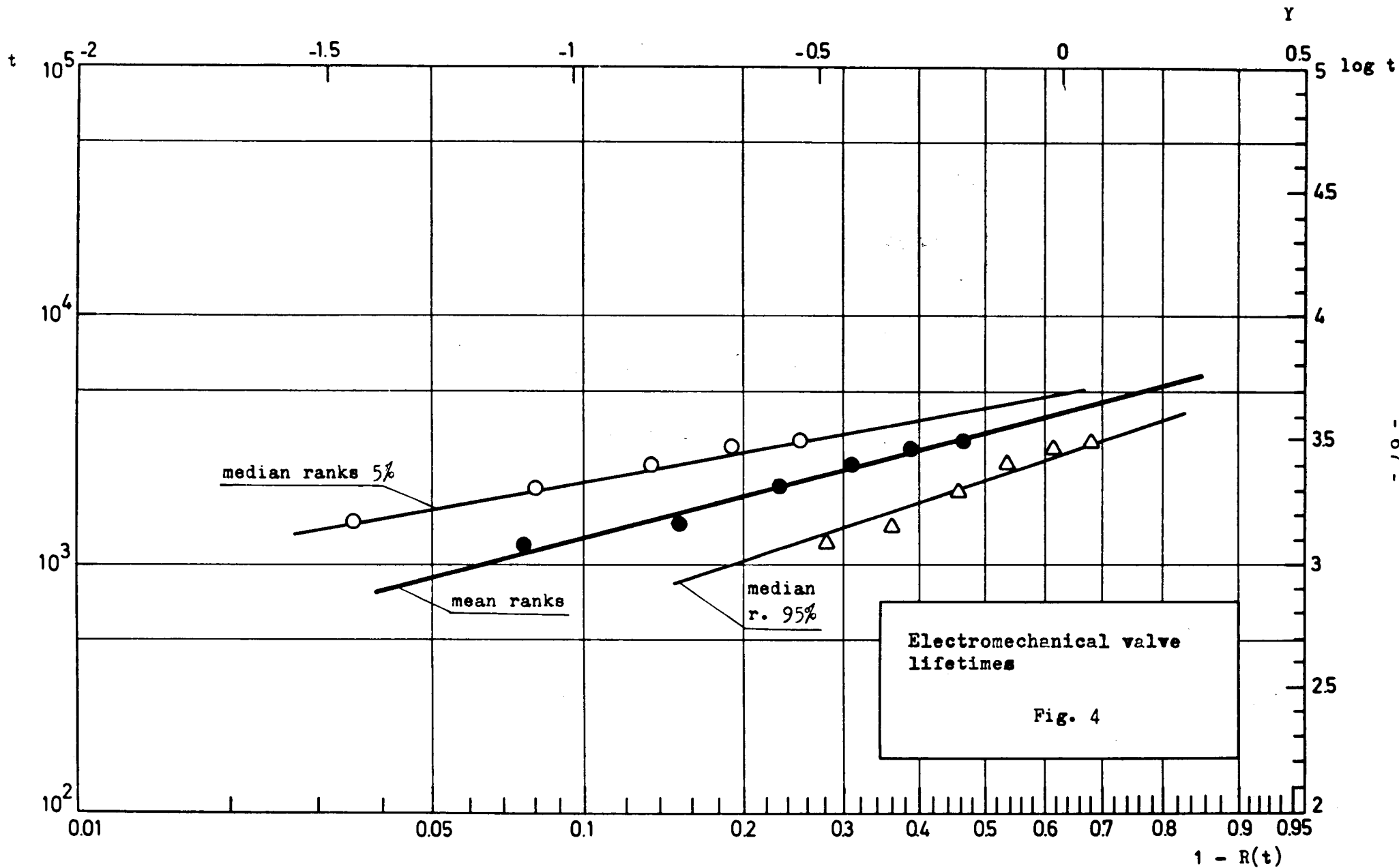
																				Sample size = N
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
1	.9500	.7764	.6316	.5271	.4507	.3930	.3481	.3123	.2831	.2589	.2384	.2209	.2058	.1926	.1810	.1707	.1616	.1533	.1458	.1391
2		.9747	.8646	.7514	.6574	.5815	.5207	.4707	.4291	.3941	.3643	.3387	.3163	.2967	.2794	.2639	.2501	.2375	.2263	.2161
3			.9830	.9024	.8107	.7286	.6587	.5997	.5496	.5069	.4701	.4381	.4101	.3854	.3634	.3438	.3262	.3102	.2958	.2826
4				.9872	.9236	.8468	.7747	.7108	.6550	.6066	.5644	.5273	.4946	.4656	.4398	.4166	.3956	.3767	.3594	.3437
5					.9898	.9371	.8712	.8071	.7486	.6964	.6502	.6091	.5725	.5400	.5107	.4844	.4605	.4389	.4191	.4010
6						.9915	.9466	.8889	.8312	.7776	.7287	.6848	.6452	.6096	.5774	.5483	.5219	.4978	.4758	.4556
7							.9927	.9536	.9023	.8499	.8004	.7547	.7129	.6750	.6404	.6090	.5803	.5540	.5299	.5078
8								.9936	.9590	.9127	.8649	.8190	.7760	.7364	.7000	.6666	.6360	.6078	.5819	.5580
9									.9943	.9632	.9212	.8771	.8343	.7939	.7563	.7214	.6891	.6594	.6319	.6064
10										.9949	.9657	.9221	.8873	.8473	.8091	.7733	.7399	.7088	.6799	.6530
11											.9953	.9695	.9339	.8959	.8583	.8222	.7881	.7560	.7260	.6990
12												.9957	.9719	.9389	.9033	.8679	.8336	.8010	.7703	.7413
13													.9960	.9740	.9431	.9097	.8762	.8436	.8125	.7829
14														.9963	.9758	.9468	.9153	.8835	.8525	.8227
15															.9966	.9773	.9501	.9203	.8901	.8604
16																.9962	.9787	.9530	.9247	.8959
17																	.9948	.9799	.9555	.9286
18																		.9930	.9810	.9578
19																			.9909	.9819
20																				.9886

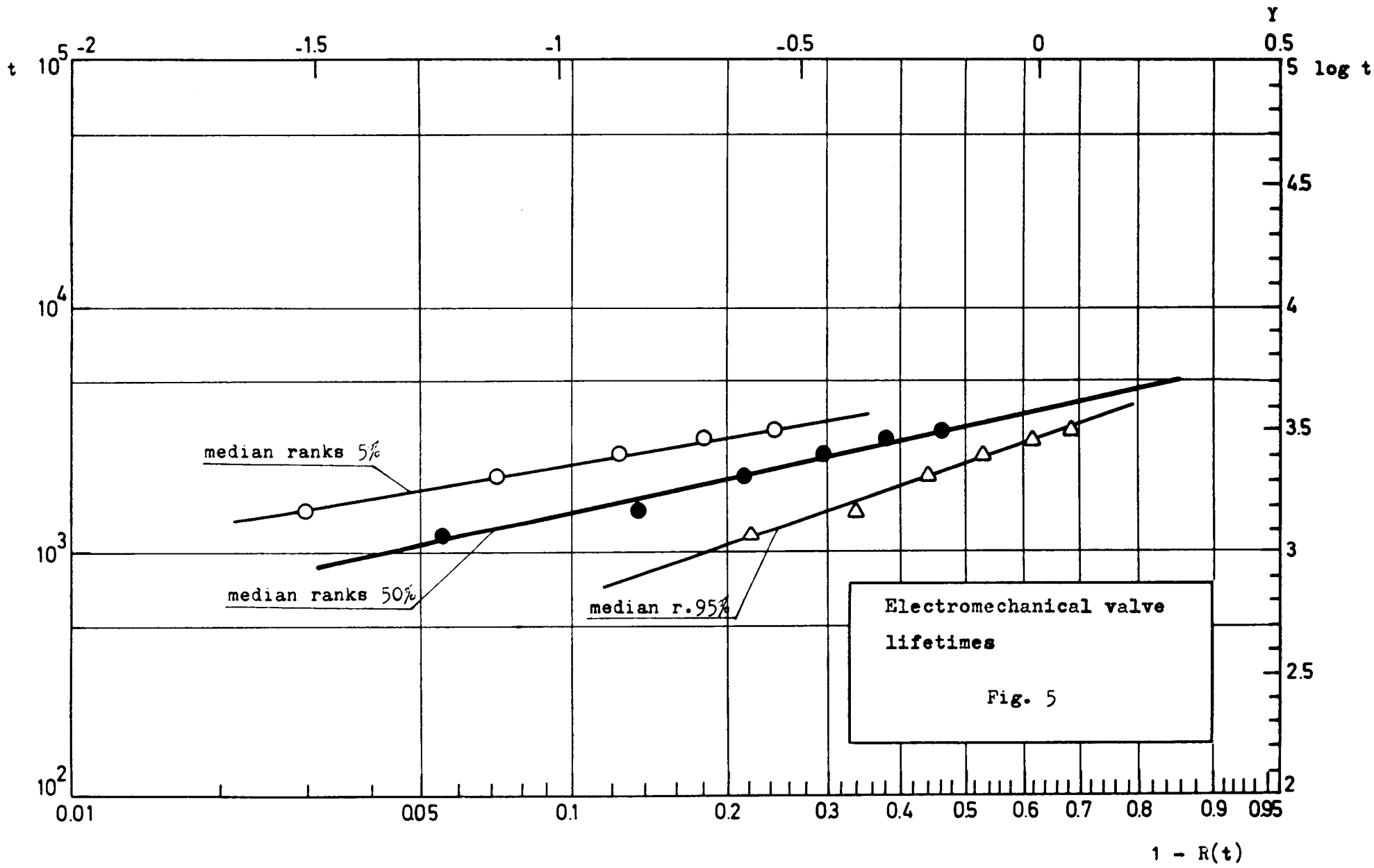
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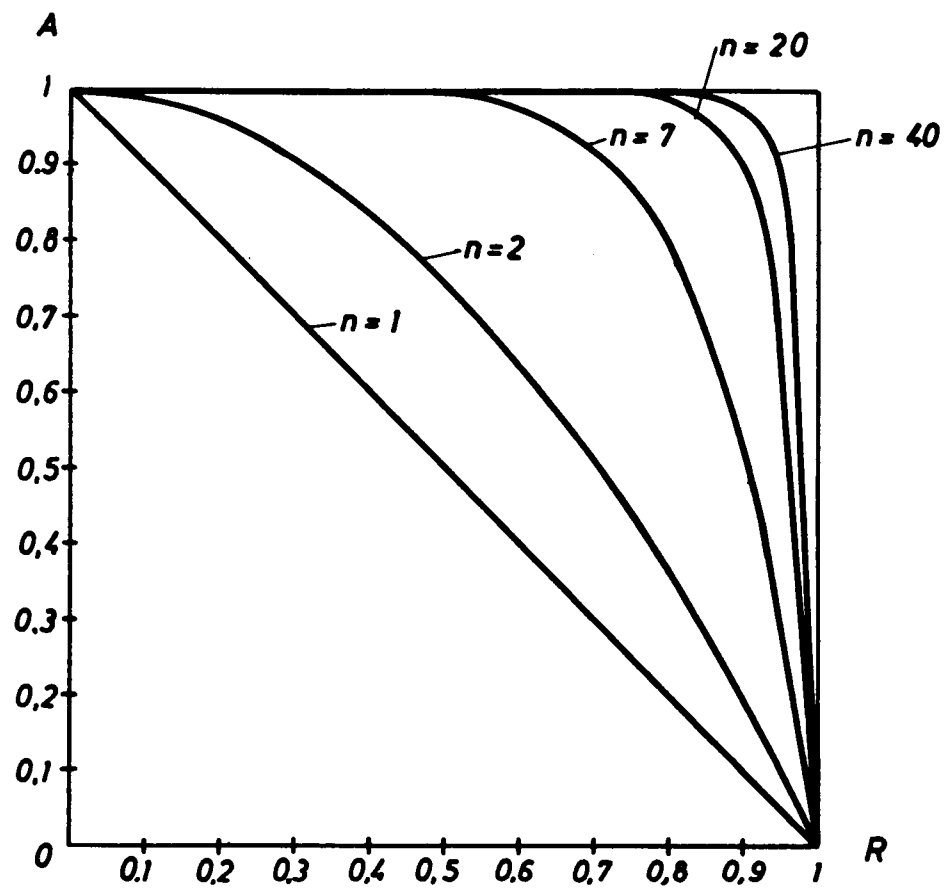


FIG. 6 Variations of confidence level A vs reliability R for various sample sizes



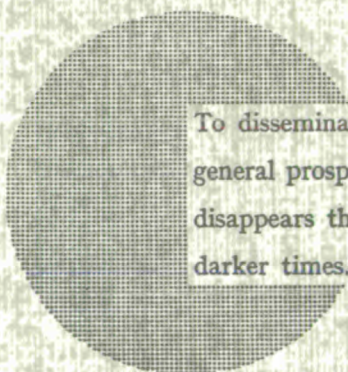
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